

AN12336

PT2001 diagnostics

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Application note

Document information

| Information | Content |
|-------------|---|
| Keywords | PT2001, combustion, engine, automotive, actuators, diagnostics, four, cylinder |
| Abstract | This application note explains how to use PT2001 diagnostics in a typical four cylinder internal combustion engine (ICE) application. |



Revision history

| Rev | Date | Description |
|-----|----------|---|
| 1.0 | 20190304 | <ul style="list-style-type: none">Initial version |

1 Introduction

This application note explains how to use PT2001 diagnostics in a typical four cylinder internal combustion engine (ICE) application. The field of powertrain is just one example where diagnostics are required at very high speed. The PT2001 diagnostics manage this through four independent microcores.

This application note seeks to address different fault cases and describes how to program the microcode to detect them during idle and actuation mode.

2 Overview

The PT2001 is a 12-channel gate driver IC for automotive engine control applications. The IC consists of five external MOSFET high-side predrivers and seven external MOSFET low-side pre-drivers. The PT2001 provides a flexible solution for the MOSFET's gate drive with a versatile control and optimized latency time. Gate drive, diagnosis, and protection are managed through four independent microcores, two code RAM, and two data RAM banks.

3 Application schematic

The PT2001 typical application controls two injection banks, one DC-DC and a pump bank.

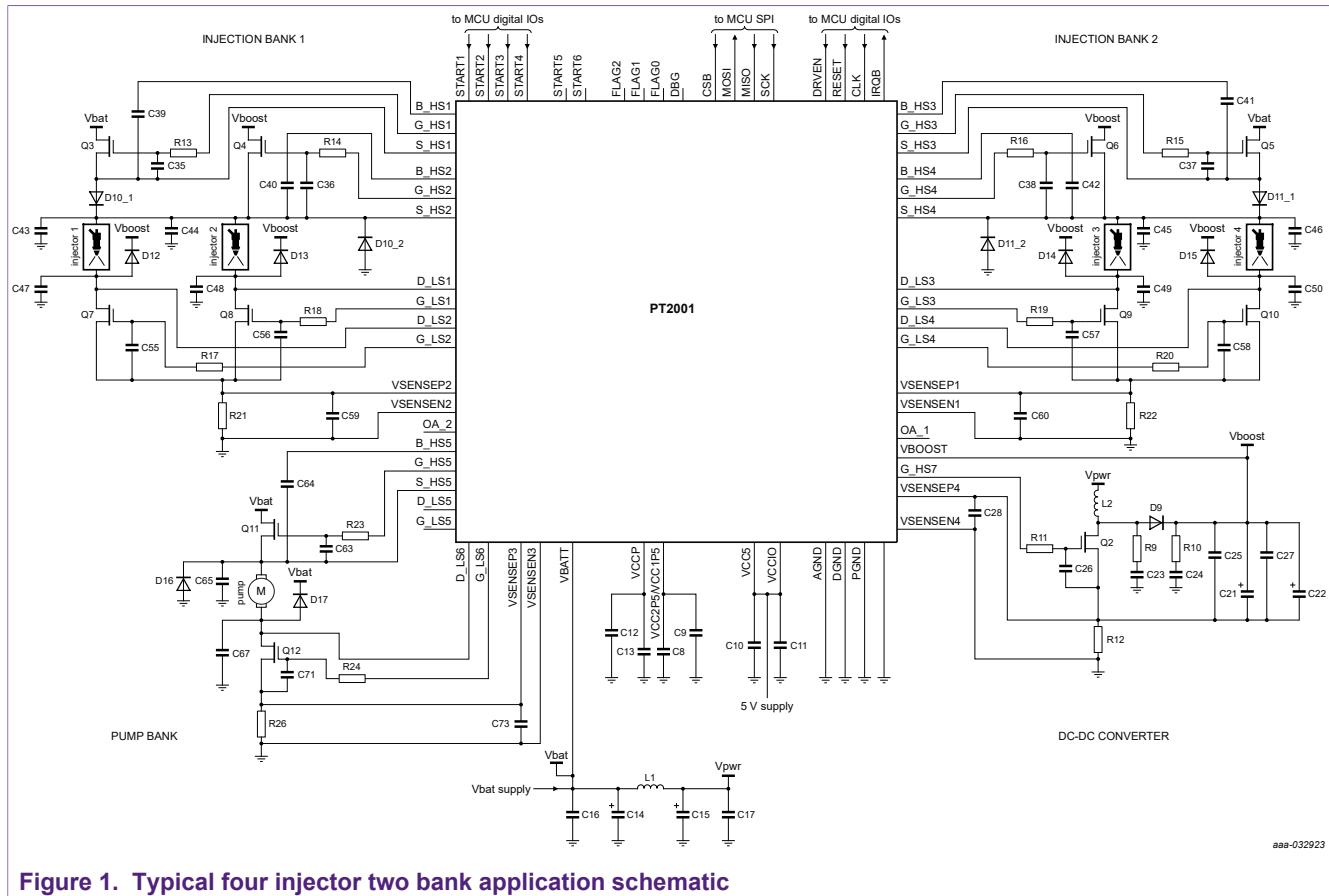


Figure 1. Typical four injector two bank application schematic

4 Application instructions

This topology can be used on the evaluation board FRDMPT2001EVM. Register settings and microcode downloads can be achieved by using the FRDM-KL25Z embedded on the FRDMPT2001EVM.

Each bank is individually managed by one microcore of the digital channel 1 as described next:

- The bank # 1 is managed by the digital microcore Uc0Ch1 with diagnostics.
- The bank # 2 is managed by the digital microcore Uc1Ch1 without diagnostics.

The two microcores of the second channel (channel 2) drive the DC-DC and the fuel pump as described next:

- The VFM (variable frequency modulation) is managed by the digital microcore Uc0Ch2.
- The fuel pump is managed by the digital microcore Uc1Ch2.

Note: This application note only focuses on BANK1 diagnostics managed by the digital microcore Uc0Ch1. See [AN4849](#) for register settings and microcode related to injection or DC-DC, unless specified in this document.

The following is the start-up sequence:

- Apply a battery voltage between 5.0 V and 72 V (with an external VCCP regulator).
- Download the registers channel configuration, main configuration, IO configuration, and diagnostic configuration.
- Download the dedicated microcode in the logic channel 1 and logic channel 2 Data RAM.
- Set '1' in the pre-flash enable bit and en dual seq bit in the Flash_enable register of channel 1 (0x100) and channel 2 (0x120).

The register configurations and the microcodes are detailed in the following sections.

Table 1. Example of injection current profile key parameters

| Parameter name | Description | Value |
|-------------------|--|-------------|
| I_{BOOST} | Current threshold in boost phase | 16.09 A |
| I_{PEAK} | Current threshold in peak phase (depends on injectors type) | 14.89 A |
| I_{HOLD} | Current threshold in hold phase | 8.89 A |
| t_{PEAK_OFF} | Fixed time for high-side switch Off in peak phase | 10 μ s |
| t_{PEAK_TOT} | Fixed time for end of peak phase | 500 μ s |
| t_{BYPASS} | Fixed time for bypass phase | 20 μ s |
| t_{HOLD_OFF} | Fixed time for high-side switch Off in hold phase | 10 μ s |
| t_{HOLD_TOT} | Fixed time for end of hold phase (timeout) | 10 ms |
| $t_{INJMAXBOOST}$ | Maximum time allowed to reach I_{BOOST} (depends on injector type) | 500 μ s |

Diagnostics interrupts description:

Diagnostics interrupts are handled in two different subroutines: automatic interrupt and software interrupt.

Status_reg_uc0 register (0x105) is used to inform MCU on error detected, and then control register is used to unlock the bank.

In all cases, the IRQB pin is set low to inform the MCU about the error detected in PT2001.

Software interrupts can be filtered by their req id (stored in Uc0_irq_status registers 0x10F):

Pre-diagnostics checks (req id = 1): interrupt occurs if the high-side V_{BOOST}/V_{BAT} , V_{DS} or V_{SRC} are low or V_{DS} low-side is low.

If an error occurs, the Status_reg_uc0 register (0x105) bit 7 sets high, Bank1 sets OFF, and MCU needs to write a 1 to the control register (0x101) bit 7 to unlock the Bank1.

Boost Error (Req id = 1): if I_{BOOST} is not reached before $t_{INJMAXBOOST} = 500 \mu s$, this number has to be set according to the injector characteristics.

If an error occurs, Status_reg_uc0 register (0x105) bit 5 sets high, Bank1 sets OFF, and MCU needs to write a 1 to the Ctrl_reg_uc0 register (0x101) bit 5 to unlock the Bank1.

Hold Error (Req id = 2): if Start signal is still high after t_{HOLD_OFF} .

If an error occurs, the Status_reg_uc0 register (0x105) bit 4 sets high, Bank1 sets OFF, and MCU needs to write a 1 to the Ctrl_reg_uc0 register (0x101) bit 4 to unlock the Bank1.

An automatic Interrupt occurs during actuation, if comparators feedback is different than the error table (see [Section 6.3 "Diagnostics configuration registers"](#)).

If an error occurs, the Status_reg_uc0 register (0x105) bit 6 sets high, Bank1 sets OFF, and MCU needs to write a 1 to the Ctrl_reg_uc0 register (0x101) bit 6 to unlock the Bank1.

Table 2. Status_reg_uc0 registers (0x105) configuration

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|-----------------|----|----|----|----|----|---|---|---------------------|-------------|----------------|---------------|---|---|---|---|
| Name | status_register | | | | | | | | | | | | | | | |
| Value | X | X | X | X | X | X | X | X | sw_interrupt_status | Auto_IrqBit | Boost_ErrorBit | Hold_ErrorBit | X | X | X | X |

Reading this register indicates the type of fault.

Table 3. Ctrl_reg_uc0 registers (0x101) configuration

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|-------------------------|----|----|----|----|----|---|---|-------------------|--------------------|----------------|---------------|---|---|---|---|
| Name | control_register_shared | | | | | | | | control_register | | | | | | | |
| Value | X | X | X | X | X | X | X | X | IdleDiag_ResetBit | Auto_Diag_ResetBit | Boost_ResetBit | Hold_ResetBit | X | X | X | X |

Depending on the status register information, one of the bits must be set to 1 to unlock the BANK.

5 Diagnostic descriptions

The PT2001 gives the possibility to check faults using two different methods:

- Automatic diagnostics (Actuation phase):

- Boost phase (HSBoost ON): automatic diagnostics are used during actuation phase; it performs a coherency check between an output and the related V_{DS} feedback (for all the outputs) and V_{SRC} feedback (for the high-side outputs only).
- Peak and Hold phase (HSBat ON): automatic diagnostics are used during actuation phase; it performs a coherency check between an output and the related V_{DS} feedback (for all the outputs) and V_{SRC} feedback (for the high-side outputs only).
- Idle diagnostics (Pre-actuation): internal voltage biasing V_{BIAS} should be applied to the load to enable diagnostics in this phase.

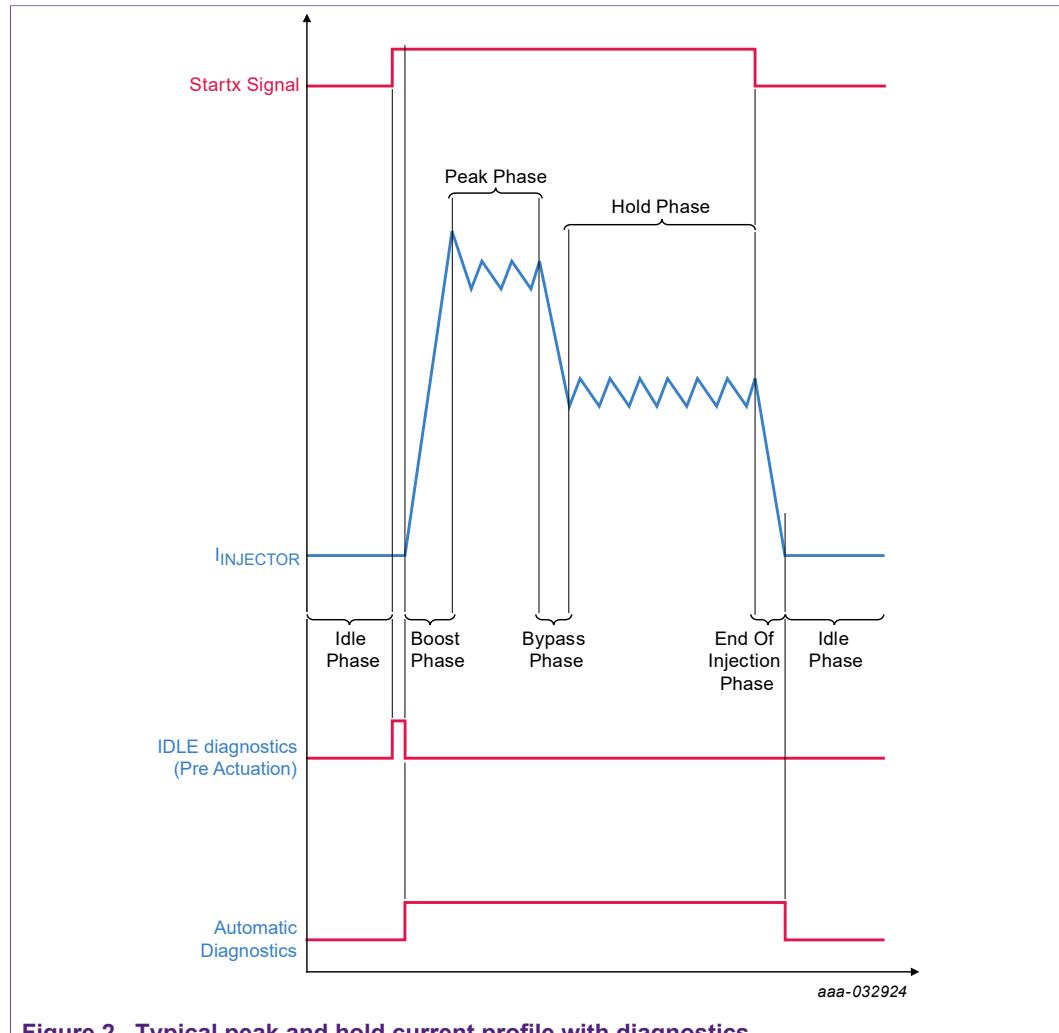


Figure 2. Typical peak and hold current profile with diagnostics

Several fault cases could occur in the application, the following sections describe most of them, and explain how the PT2001 is able to detect them.

5.1 Idle diagnostics (pre-actuation)

As described in Figure 2, idle diagnostics start after a rising edge on the start 1 or start 2 (Bank 1). A voltage biasing V_{BIAS} should be applied to the load, to enable electrical diagnosis while the external load is not actuating the power stage.

This V_{BIAS} voltage is generated by:

- the activation of the SRC_{PUX} pull-up voltage source connected to each of the S_HSx pins. Each pull-up voltage source is supplied from VCC5.
- the activation of each SRC_{PDX} pull-down current source connected to each of the D_LSx pins. Each pull-down voltage source is referenced to ground.

When the battery voltage V_{BATT} is in the nominal range or greater, the external load is biased at a minimum voltage of typically 3.8 V. In a low battery voltage condition ($V_{BATT} < 8.0$ V), the load is biased at half the V_{BATT} voltage, to guarantee symmetrical voltage margins to high-side and low-side VDS comparators.

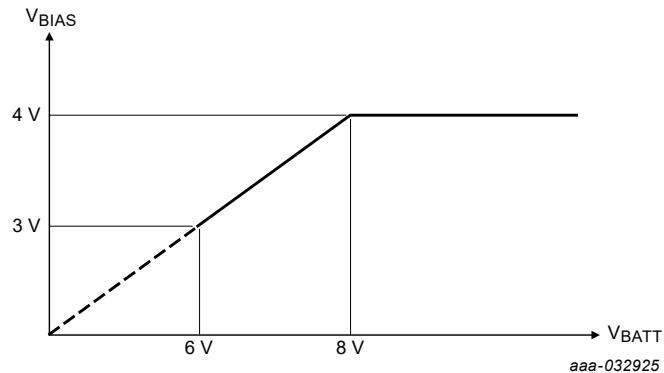


Figure 3. Biasing voltage vs. V_{BATT}

The bias generators can be kept ON even during actuation, to control the voltage on the source, even if the MOSFET is OFF. This does not impact the application, because of their low strength. If at least one MOSFET is turned ON, it fixes the voltage on the load and does not affect the bias.

These pre-actuation diagnostics are used to ensure the injectors can be turned ON safely. If an error occurs in any of the following cases, the PT2001 keeps Bank 1 OFF until the MCU writes a 1 through the SPI to the Ctrl_reg_uc0 register (0x101) bit 7.

5.1.1 Normal behavior

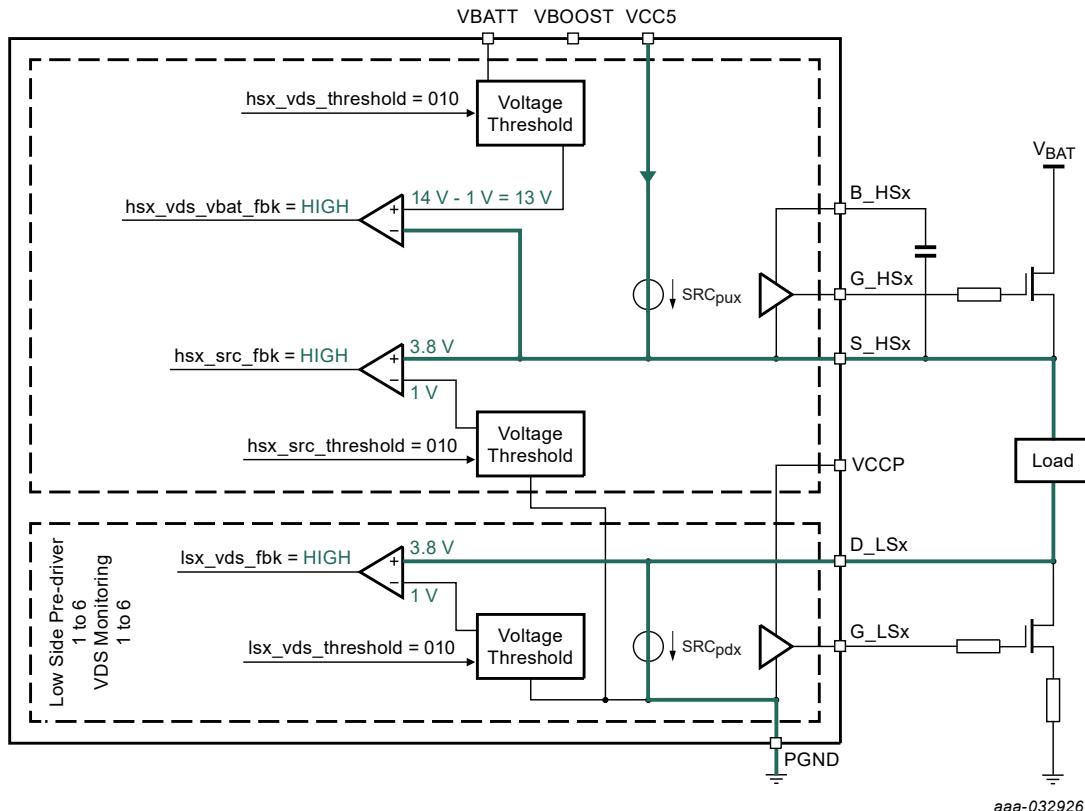


Figure 4. Idle normal mode

During normal operation, a current limited pull-up voltage source (SRC_{PUX}) generates a voltage on S_{HSx} (minimum 3.8 V). The current goes to the load and to a pull-down current source on D_{LSx}, generating a 3.8 V minimum voltage. Drain source voltage on the high-side is not monitored directly, and since there is no pin for the drain, monitoring is directly done from V_{BAT} or V_{BOOST}, and only HS2 and HS4 can use V_{BOOST} as a reference. Voltage thresholds are selected to be lower than the voltage generated.

Table 4. Normal mode truth table

| Error case | LSx_vds_fbk | HSx_src_fbk | HSx_vds_Vbat_fbk | S_HSx voltage V _{BAT} | D_LSx voltage |
|-------------|-------------|-------------|------------------|--------------------------------|---------------|
| Normal mode | 1 | 1 | 1 | 3.8 | 3.8 |

5.1.2 High-side source or low-side drain shorted to GND

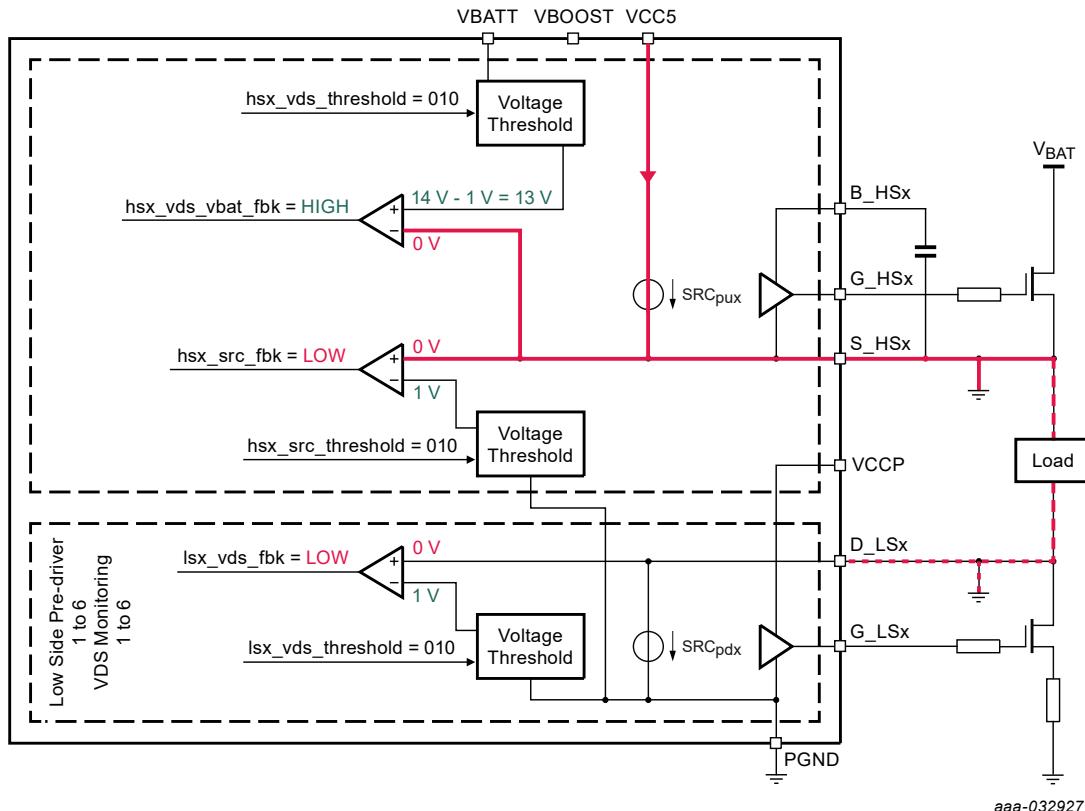


Figure 5. High-side source or low-side drain shorted

In cases where the high source (S_HSx) shorts to GND or the low-side drain (D_LSx) shorts to GND, the current limited voltage source pulls to ground, and the voltage on S_HSx and D_LSx is 0 V. A diagnostic error is detected, and since the high-side V_{SRC} and low-side V_{DS} feedback are low, the bank does not turn ON.

Table 5. S_HSx or D_LSx shorted to GND truth table

| Error case | LSx_vds_fbk | HSx_src_fbk | hsx_vds_Vbat_fbk | S_HSx voltage V_{BAT} | D_LSx voltage |
|----------------|-------------|-------------|------------------|-------------------------|---------------|
| Normal mode | 1 | 1 | 1 | 3.8 | 3.8 |
| D_LS GND short | 0 | 0 | 1 | 0 | 0 |

5.1.3 Drain source low-side shorted to GND

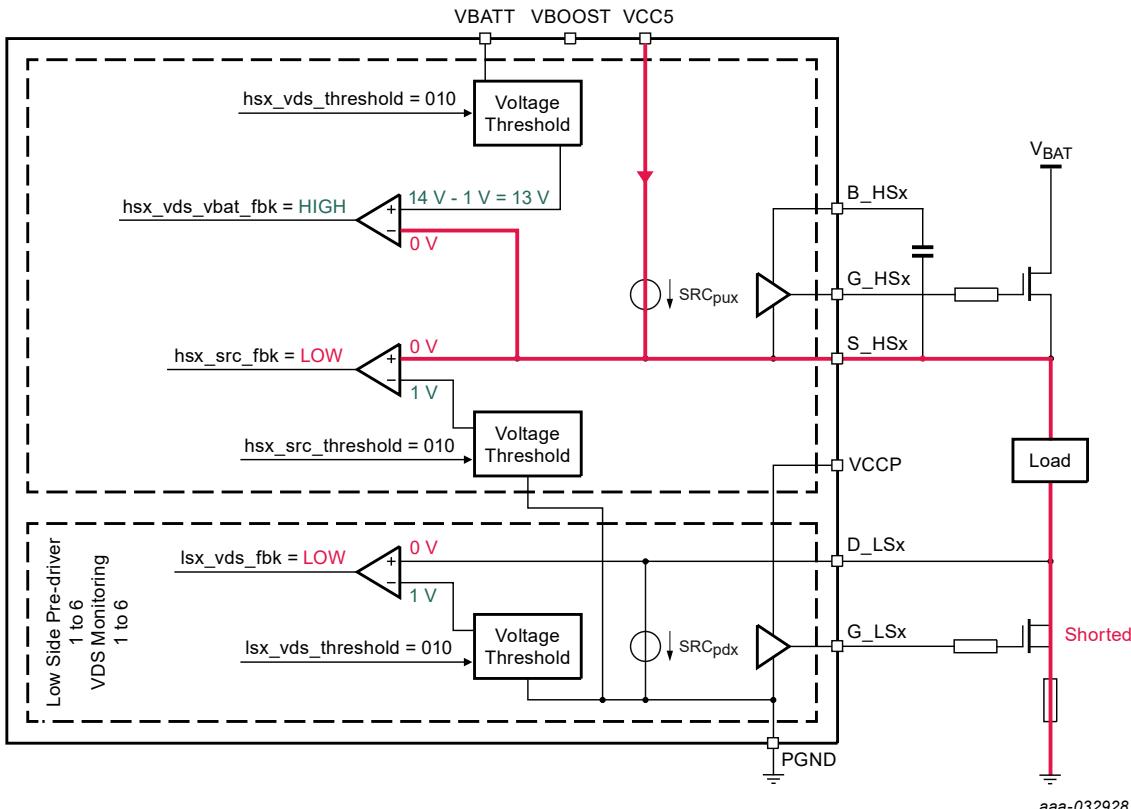


Figure 6. Low-side drain source shorted

In cases where the low-side drain source shorts, D_LSx pulls to 0 V, the current limited voltage source pulls to ground, and the voltage on S_HSx and D_LSx is 0 V. A diagnostic error is detected, since the high-side V_{SRC} and low-side V_{DS} feedback are low.

Table 6. Drain source low-side shorted truth table

| Error case | LSx_vds_fbk | HSx_src_fbk | hsx_vds_Vbat_fbk | S_HSx voltage V _{BAT} | D_LSx voltage |
|-----------------------------|-------------|-------------|------------------|--------------------------------|---------------|
| Normal mode | 1 | 1 | 1 | 3.8 | 3.8 |
| Low-side drain source short | 0 | 0 | 1 | 0 | 0 |

5.1.4 Drain source high-side shorted to VBAT

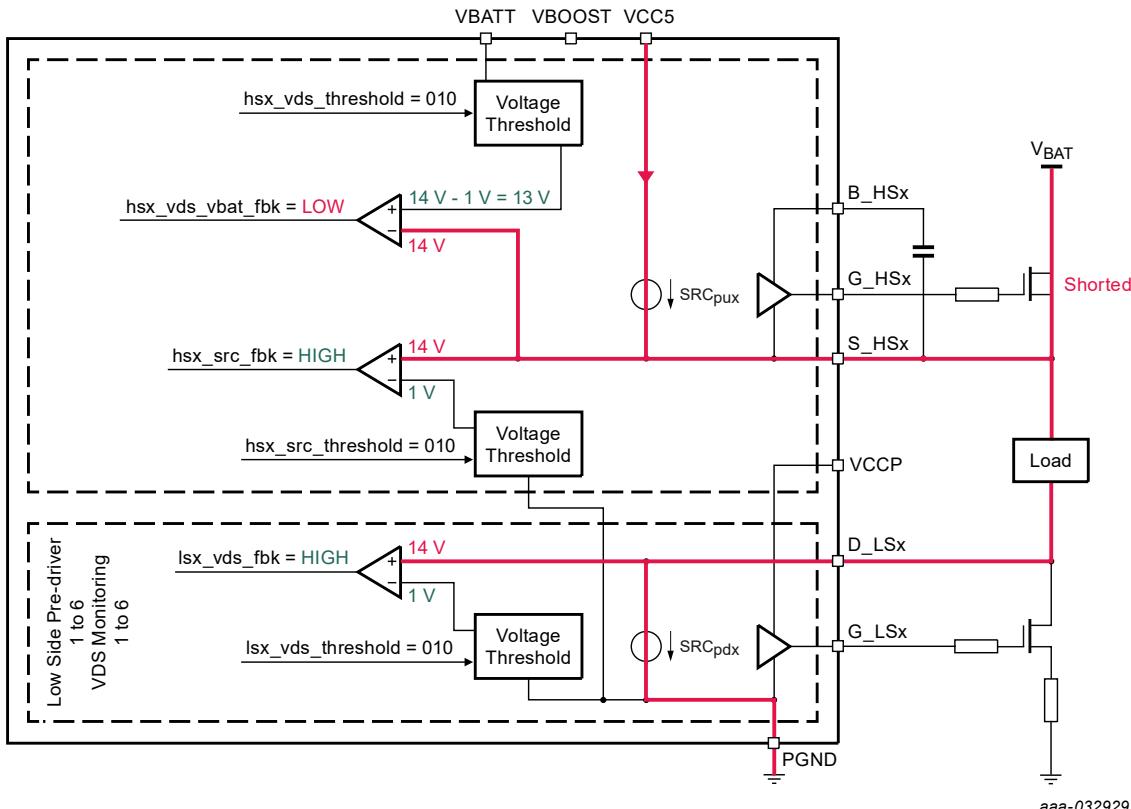


Figure 7. High-side drain source shorted

The diagnostic fails in cases where the high-side drain source shorts. As a consequence, S_HSx and D_LSx pulls up to V_{BAT}, the difference between drain and source on the high-side goes negative, resulting in low feedback on the high-side V_{DS}.

Table 7. Drain source high-side shorted truth table

| Error case | LSx_vds_fbk | HSx_src_fbk | HSx_vds_Vbat_fbk | S_HSx voltage V _{BAT} | D_LSx voltage |
|------------------------------|-------------|-------------|------------------|--------------------------------|---------------|
| Normal mode | 1 | 1 | 1 | 3.8 | 3.8 |
| High-side drain source short | 1 | 1 | 0 | 14 | 14 |

5.1.5 Openload

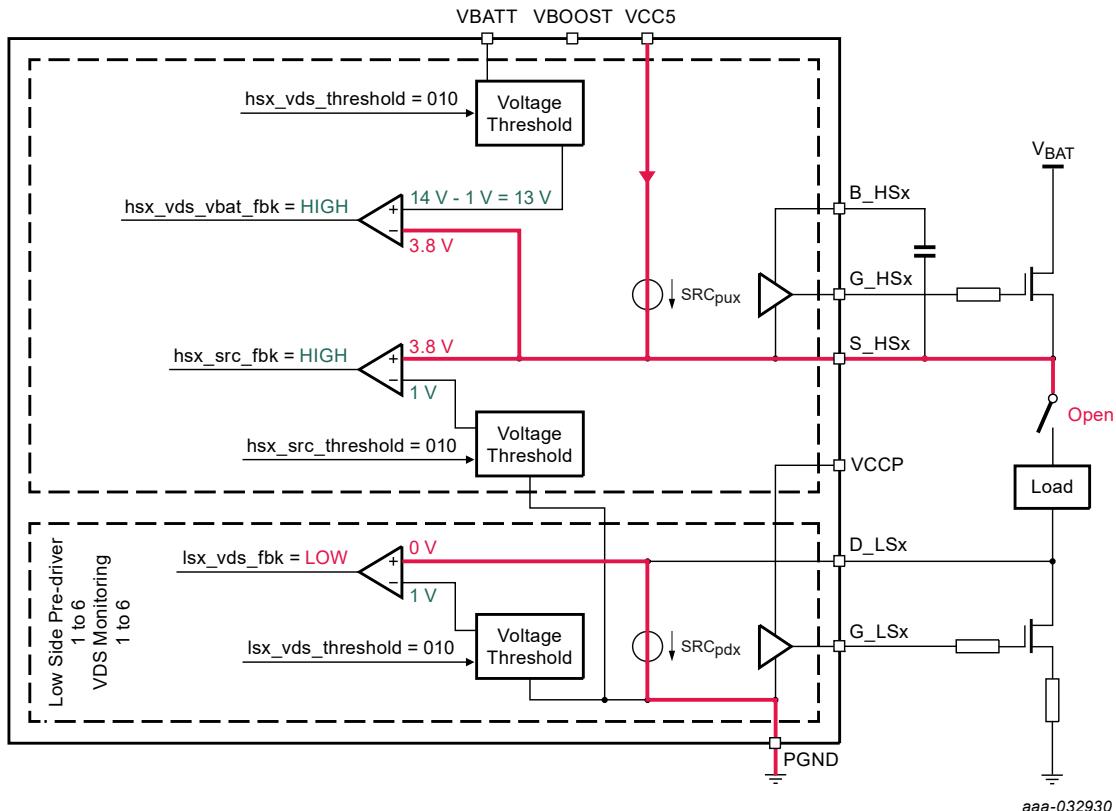


Figure 8. Openload

If one of the sides of the load is not connected properly, there is no current path between S_HSx and D_LSx. The voltage on D_LSx is forced to ground, because of the SRC_{PDX} current pull-down. The diagnostic fails, because the low-side V_{DS} feedback is low.

Table 8. Openload truth table

| Error case | LSx_vds_fbk | HSx_src_fbk | Hsx_vds_Vbat_fbk | S_HSx voltage V _{BAT} | D_LSx voltage |
|-----------------------|-------------|-------------|------------------|--------------------------------|---------------|
| Normal mode | 1 | 1 | 1 | 3.8 | 3.8 |
| Openload on low-side | 0 | 1 | 1 | 3.8 | 0 |
| Openload on high-side | 0 | 1 | 1 | 3.8 | 0 |

5.1.6 Faults not detected in idle phase

There are different cases that cannot be detected in the idle phase:

- High-side V_{BAT} or V_{BOOST} open: not possible to be detected since both are OFF in idle phase
- LS open: not possible to be detected since it is OFF in idle phase
- Short between load pins: not possible to detect, because it allows the bias current to pass through

All these faults are detected in the actuation mode only.

5.2 Actuation phase

The bias voltage used for idle diagnostics is kept ON, to predict the voltage on each pin even if the MOSFETs are OFF. In this case, when the MOSFETs are OFF, there is a 3.8 V voltage on the high-side source. In each case, if an error occurs, the PT2001 turns bank 1 OFF, keeps it OFF, and sets the Status_reg_uc0 register (0x105) bit 6 high until the MCU writes a 1 to the control register bit 6.

5.2.1 Actuation diagnostics peak and hold phase (HS Boost OFF, HS Bat ON, LS ON)

5.2.1.1 Normal mode

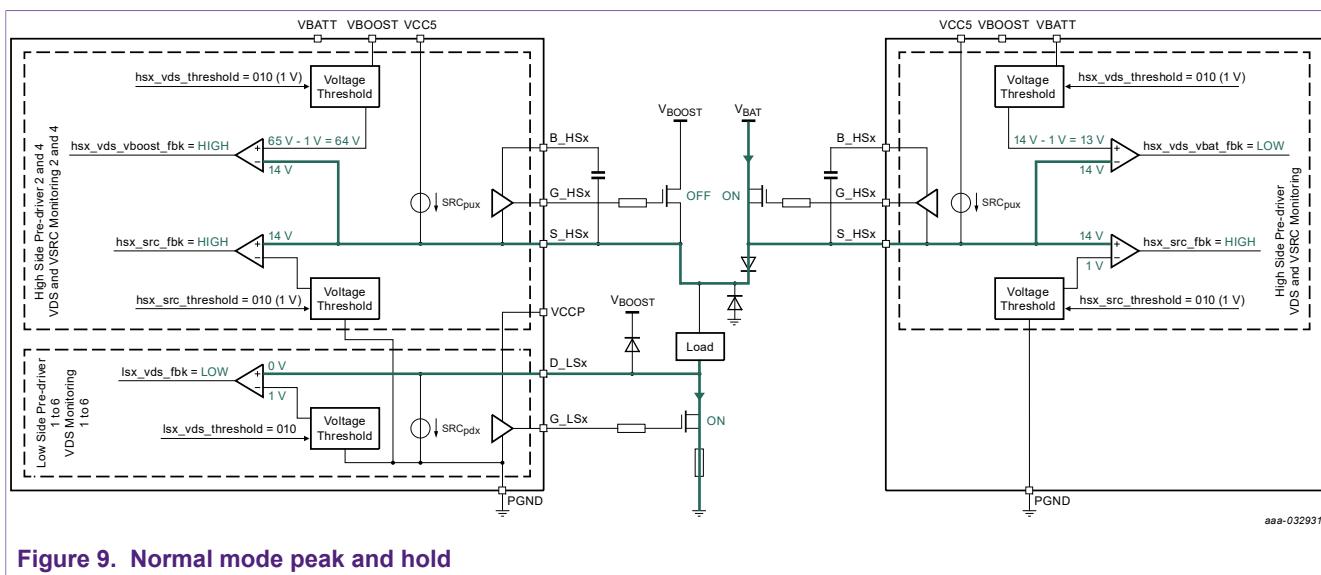


Figure 9. Normal mode peak and hold

During peak and hold phase, the low-side is fully ON and V_{BAT} high-side is controlled in PWM to regulate the current inside the injector.

To have a device as flexible as possible, detection error during automatic diagnostics is configurable for each low-side and high-side. To configure which case will lead the device to an error, it is necessary to set the registers *Error_table* for each low-side V_{DS} , high-side V_{DS} , and high-side S_{RC} where diagnostics are needed (see [Section 6.3 "Diagnostics configuration registers"](#)). In Normal mode, the PT2001 comparator outputs should be in the following state:

Table 9. Actuation in Normal mode truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|-------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |

5.2.1.2 High-side (Bat or Boost) source shorted to GND

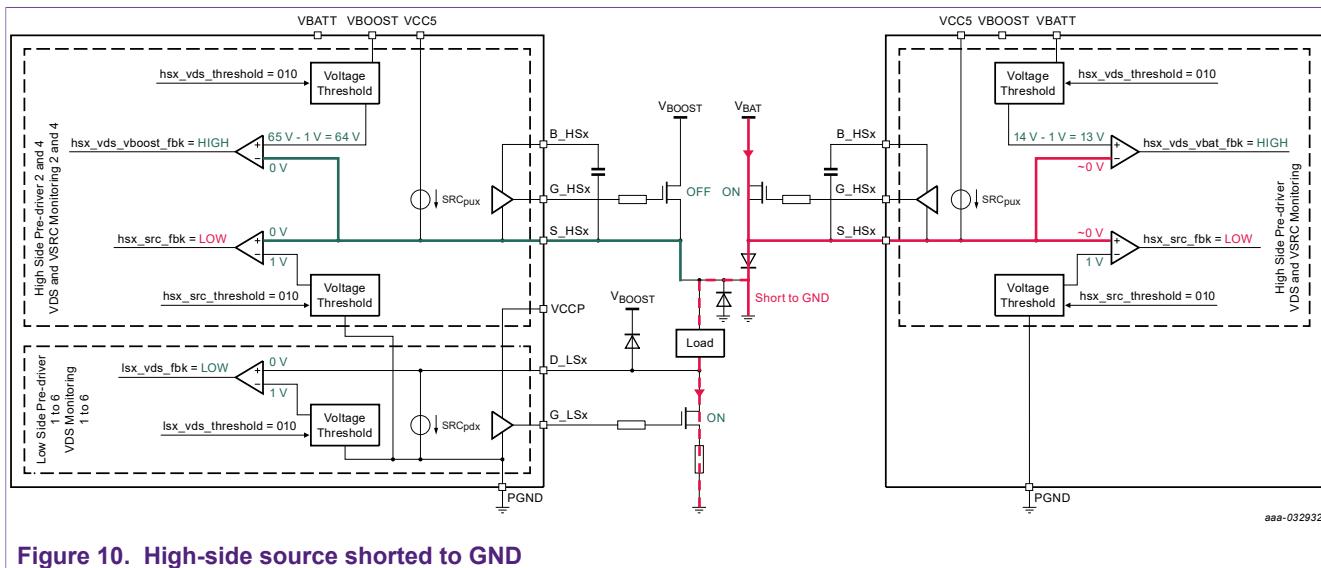


Figure 10. High-side source shorted to GND

When S_HSx shorts to GND, the PT2001 detects an overcurrent, due to the V_{DS} monitoring on the V_{BAT} high-side. The high-side shuts down as soon as the current is substantial enough to generate a higher drop across the MOSFET than the threshold. In this case, it is important to set a threshold (1.0 V, in this case) and a filter time to the lowest value allowed by the application, to quickly detect it (see [Section 6.3.1.1 "Filter time"](#)). The automatic diagnostic fails, because high-side V_{DS} feedback is high.

Table 10. High-side source shorted to GND truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsdc_Vboost_fbk |
|--|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |
| S_HSx V_{BAT} or V_{BOOST} GND short | 0 | 0 | 1 | 1 | 0 |

This case is also applicable when there is a short between the two load pins, substantial current flows inside V_{BAT} HS and LS until the difference between drain and source is higher than the threshold.

5.2.1.3 High-side V_{BOOST} short drain source

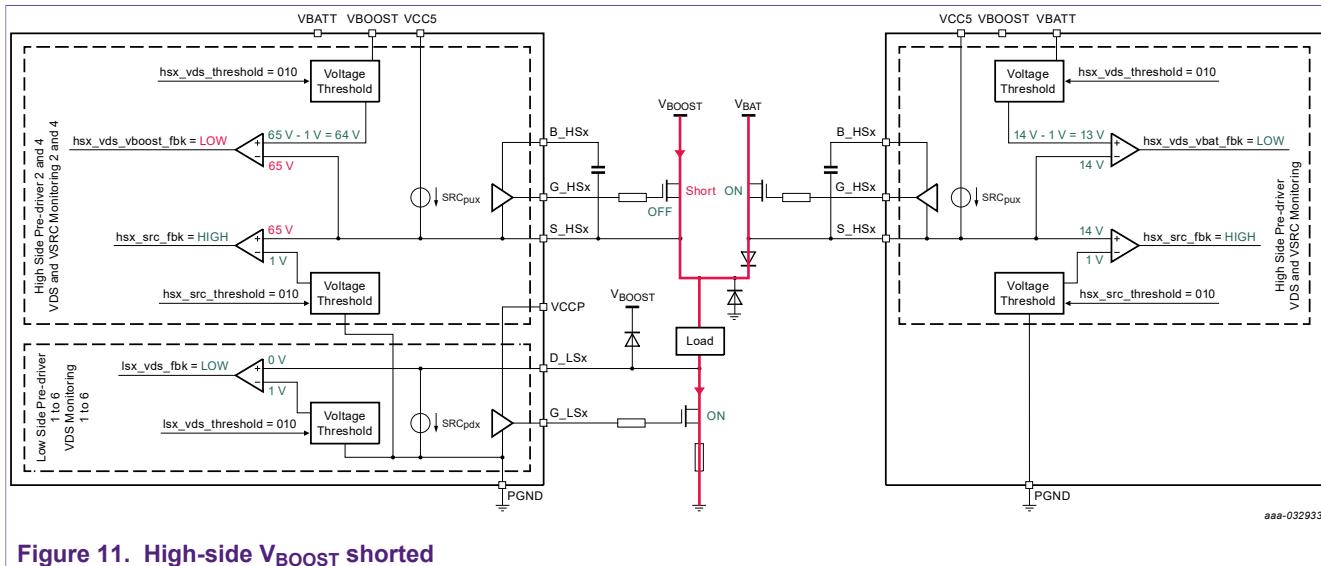


Figure 11. High-side V_{BOOST} shorted

During a peak and hold phase, V_{BOOST} high-side should be OFF, but if there is a short-circuit between the drain and source, the voltage on the V_{BOOST} high-side source rises to V_{BOOST} . The automatic diagnostic fails, because V_{DS} on the V_{BOOST} high-side is low.

Table 11. High-side V_{BOOST} drain source shorted truth table

| Error case | LSx_vds_fbk | $HSx_src_vbat_fbk$ | $HSx_vds_Vbat_fbk$ | $HSx_vds_Vboost_fbk$ | $HSx_src_Vboost_fbk$ |
|---------------------------|-----------------|-----------------------|-----------------------|-------------------------|-------------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |
| HSboot drain source short | 0 | 1 | 0 | 0 | 1 |

5.2.1.4 High-side V_{BAT} open

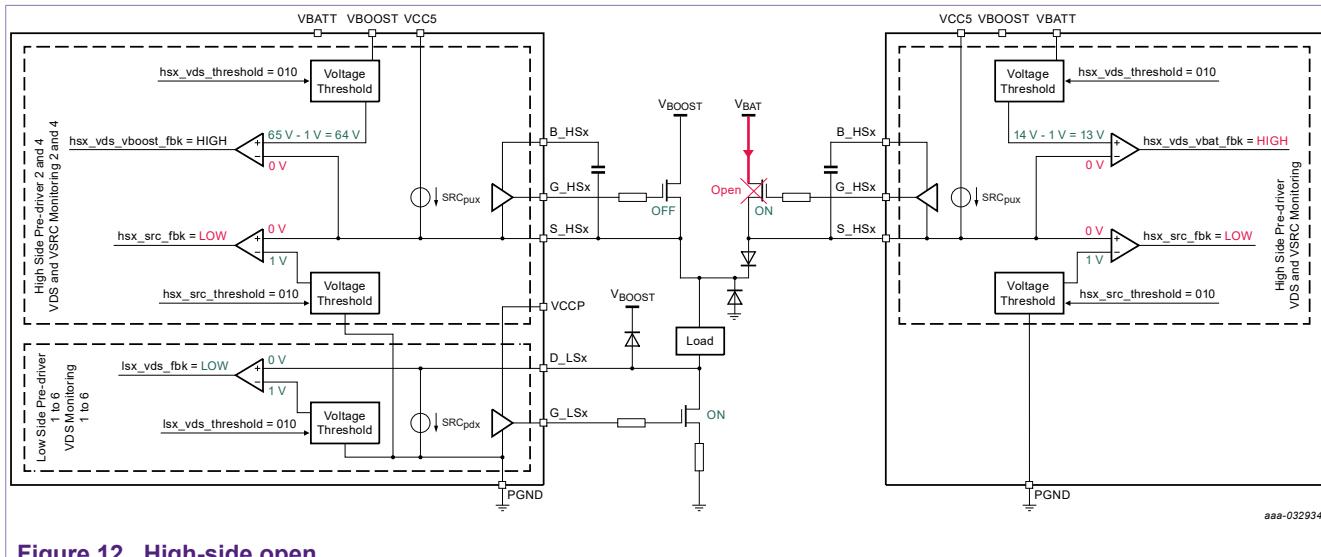


Figure 12. High-side open

During peak and hold phase, high-side V_{BAT} is ON. If open or not controlled properly, S_{HSx} voltage will be lower than expected. The automatic diagnostic fails because on V_{BAT} high-side, the V_{DS} feedback is high and V_{SRC} feedback is low.

Table 12. High-side V_{BAT} open truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|--------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |
| HS vbat open | 0 | 0 | 1 | 1 | 0 |

This case is only detectable in actuation mode.

5.2.1.5 Low-side open

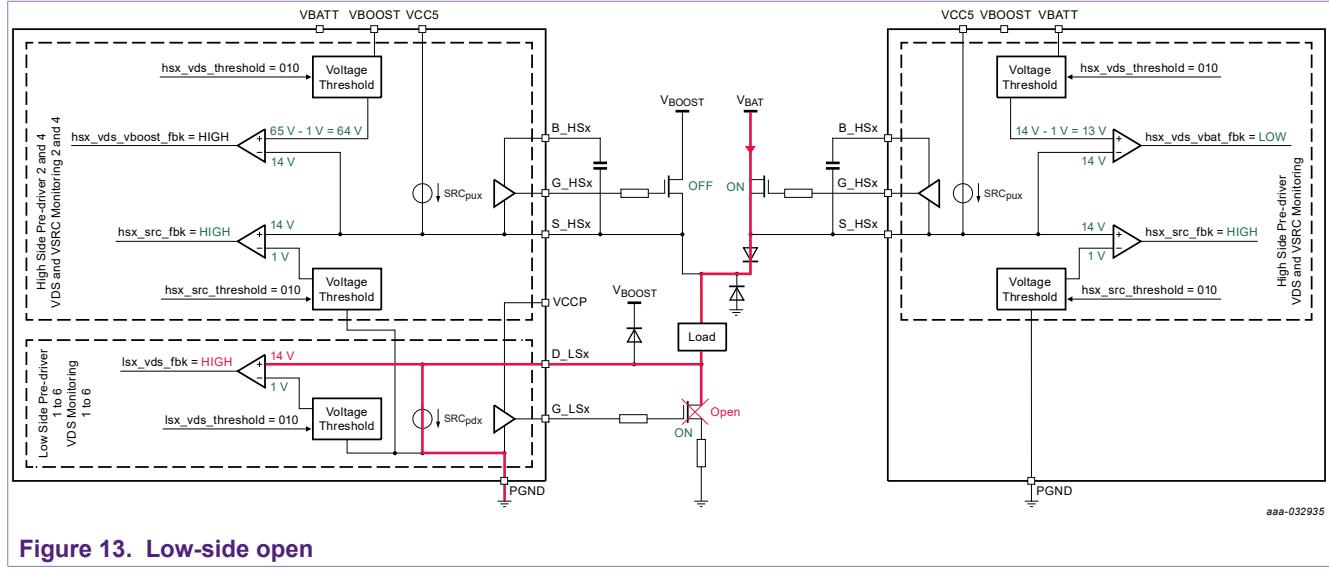


Figure 13. Low-side open

With the low-side open, current on the D_LSx pin flows through the load to the internal pull-down (SCR_{PDX}) and the voltage rises to V_{BAT} . Automatic diagnostics fail, because the low-side V_{DS} feedback is high.

Table 13. Low-side open truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|-------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |
| LS open | 1 | 1 | 0 | 1 | 1 |

This is one case only detectable in actuation mode.

5.2.1.6 Drain low-side shorted to V_{BAT} or V_{BOOST}

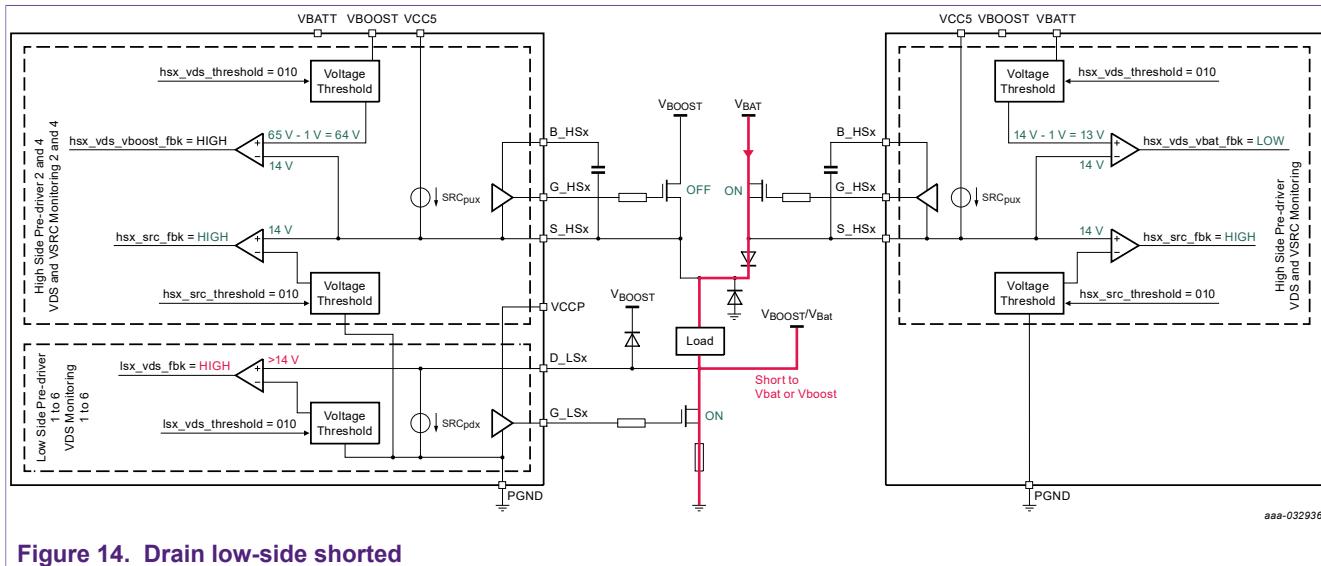


Figure 14. Drain low-side shorted

When the low-side drain is shorted to V_{BAT} or V_{BOOST} (low probability case), the voltage on D_{LSx} rises to V_{BAT}/V_{BOOST} . Voltage thresholds and filter times must be set to the lowest value allowed by the application, to detect the error as fast as possible. The automatic diagnostic fails, because the low-side V_{DS} feedback is high.

Table 14. D_{LS} battery short truth table

| Error Case | LSx_{vds_fbk} | $HSx_{src_vbat_fbk}$ | $HSx_{vds_Vbat_fbk}$ | $HSx_{vds_Vboost_fbk}$ | $HSx_{src_Vboost_fbk}$ |
|---|------------------|------------------------|------------------------|--------------------------|--------------------------|
| Normal mode | 0 | 1 | 0 | 1 | 1 |
| D_{LS} battery short depending on external MOS behavior | 1 | 1 | 0 | 1 | 1 |

5.2.1.7 Cases undetectable during peak and hold phase

There are different cases that cannot be detected during peak and hold phase:

- Drain low-side shorted to GND: not detectable since the low-side is ON, in this case (detectable in idle phase)
- High-side V_{BAT} drain source shorted: not detectable since the high-side is ON, in this case (detectable in idle phase)
- High-side V_{BOOST} open: not detectable since the high-side V_{BOOST} is OFF in this mode (detectable during V_{BOOST} phase)

5.2.2 Actuation diagnostics boost phase (HS Boost ON, HS Bat ON, LS ON)

During boost phase, boost voltage is used to turn the injector ON as fast as possible, high-side V_{BOOST} and low-side are ON. The high-side V_{BAT} source needs to be turned ON, to avoid errors during diagnostics, which has no impact on the application. Another option would be to disable automatic diagnostics on the high-side V_{BAT} source during boost phase.

In this example, the PT2001 automatic diagnostics are configured using instruction `endiags` (see [Section 7 "Application source code"](#)). During actuation phase, automatic diagnostics monitor HS V_{BAT} V_{DS} , HS V_{BAT} V_{SRC} , HS V_{BOOST} V_{DS} , and LS V_{DS}

continuously. To simplify the diagnostics code, HS V_{BAT} is kept ON during boost phase to avoid unwanted errors on the V_{BAT} source.

5.2.2.1 Normal mode

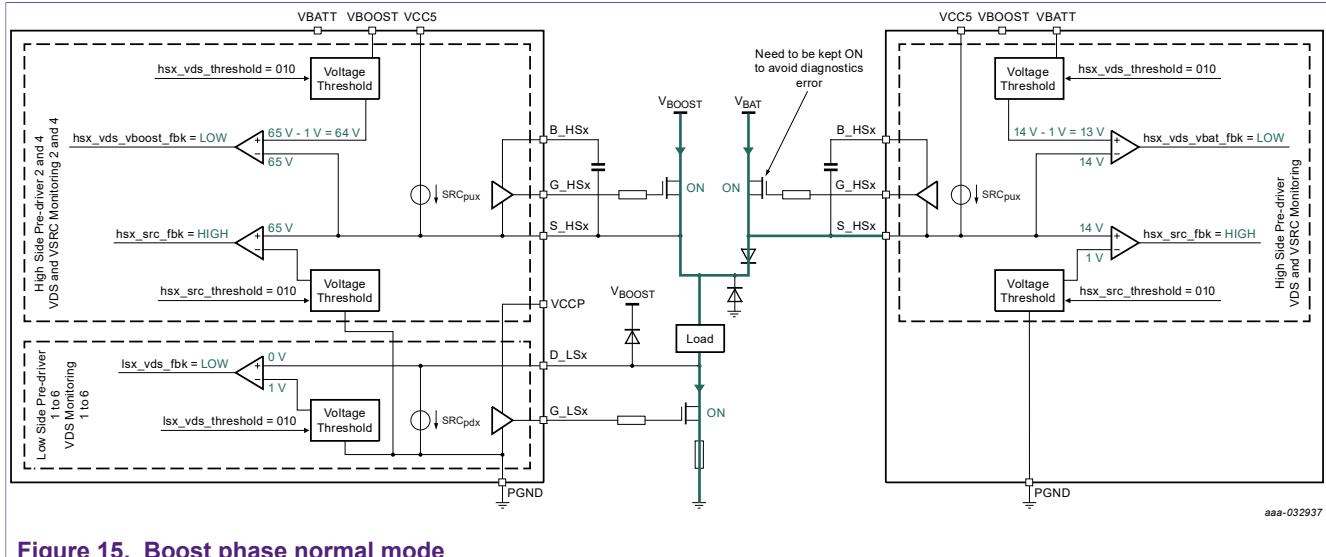


Figure 15. Boost phase normal mode

During boost phase, the high-side boost is fully ON to reach boost current as fast as possible, high-side V_{BAT} is ON (for diagnostic purposes), and the low-side is fully ON. As with the peak and hold phase, the high-side V_{BOOST} error table must be set-up accordingly (see [Section 6.3 "Diagnostics configuration registers"](#)).

Table 15. Boost phase normal mode truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrx_Vboost_fbk |
|-------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 0 | 1 |

5.2.2.2 High-side boost source shorted to GND

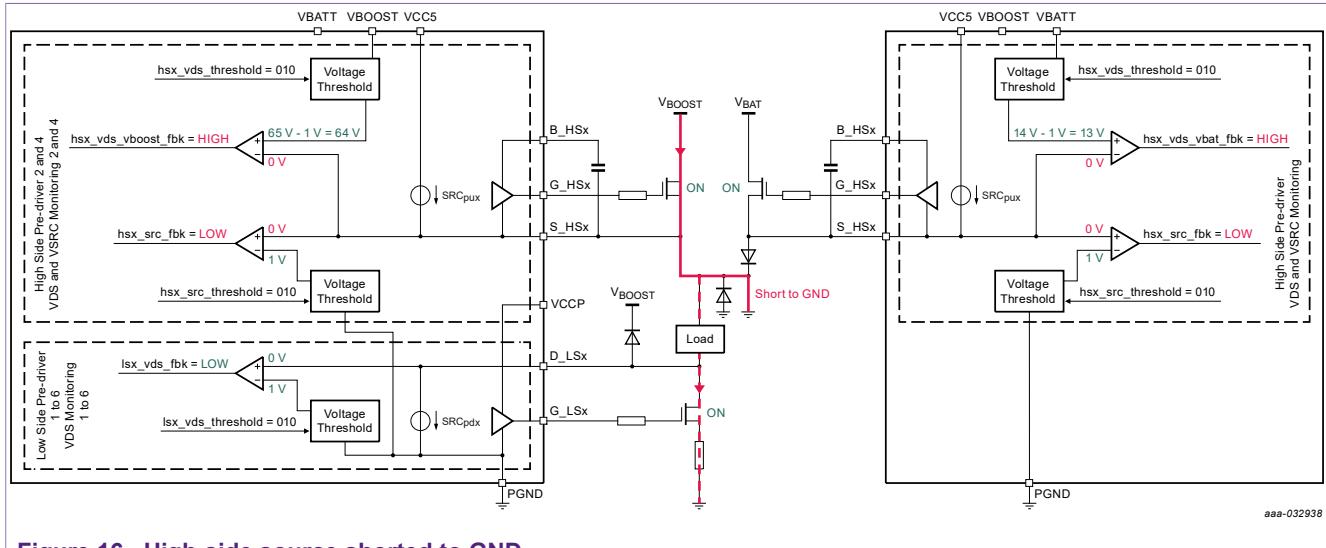


Figure 16. High-side source shorted to GND

The same behavior as in the peak and hold phase except this time the short is from V_{BOOST} to GND. The comparator threshold must be set as low as possible to detect the

overcurrent faster and avoid any damage to the MOS. The automatic diagnostic on high-side V_{BOOST} fails because V_{DS} monitoring is high.

Table 16. High-side boost source shorted to GND truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|--------------------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 0 | 1 |
| HSbat drain source short | 0 | 0 | 1 | 1 | 0 |

5.2.2.3 High-side V_{BOOST} open

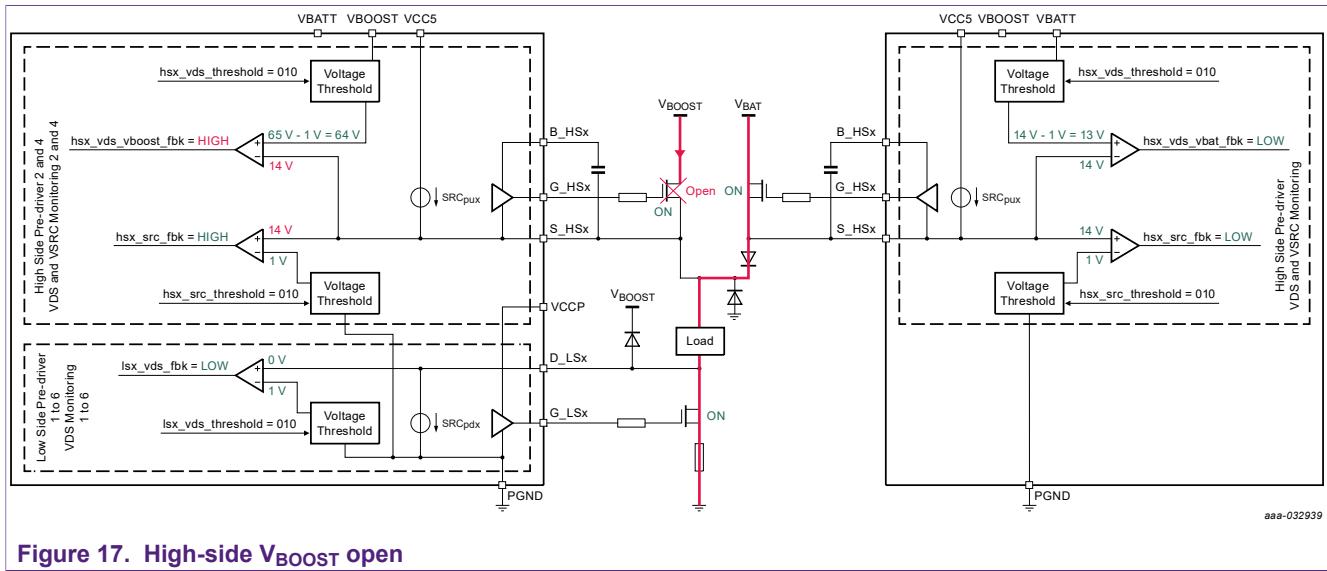


Figure 17. High-side V_{BOOST} open

When V_{BOOST} high-side is open, the voltage on S_{HSx} floats and forced to 0 V, due to the parasitic leakage on the S_{HSx} pin. The automatic diagnostic on high-side V_{BOOST} fails because V_{DS} feedback is high.

Table 17. High-side boost open truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|---------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 0 | 1 |
| HS vboot open | 0 | 1 | 0 | 1 | 1 |

This case is undetectable in idle phase.

5.2.2.4 Low-side open

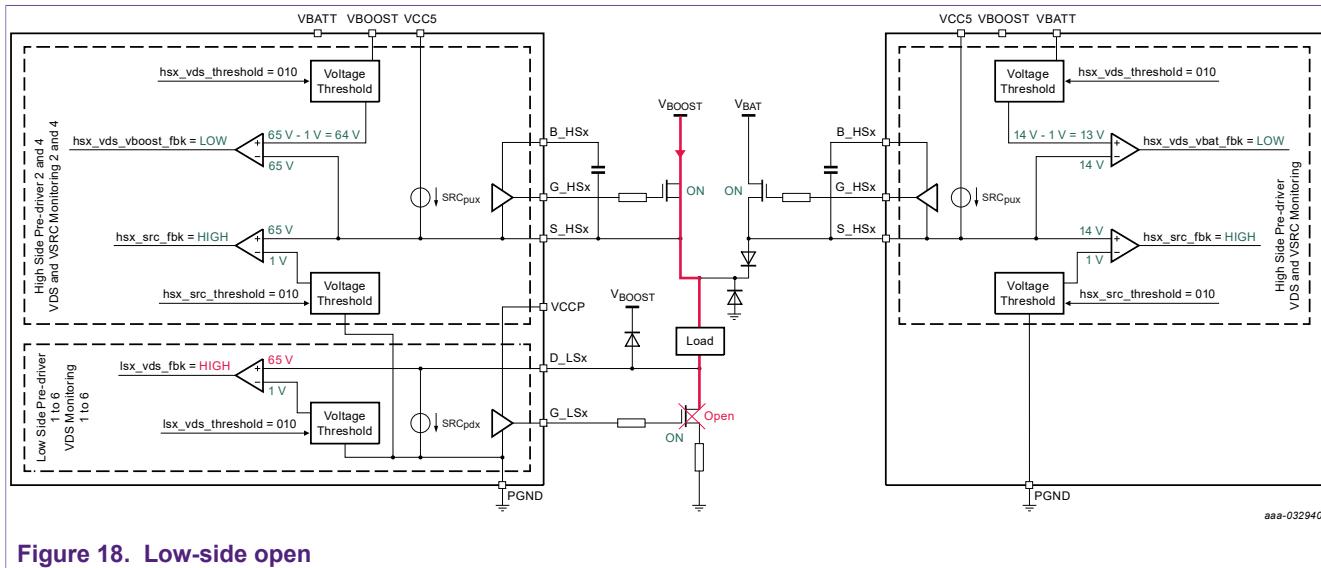


Figure 18. Low-side open

When the low-side is not connected properly, the voltage on D_LSx is around a V_{BOOST} of 65 V. The automatic diagnostic fails due to V_{DS} feedback on the low-side.

Table 18. Low-side open truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_src_Vboost_fbk |
|-------------|-------------|------------------|------------------|--------------------|--------------------|
| Normal mode | 0 | 1 | 0 | 0 | 1 |
| LS open | 1 | 1 | 0 | 0 | 1 |

This case is undetectable in idle phase.

5.2.2.5 Drain low-side shorted to V_{BAT} or V_{BOOST}

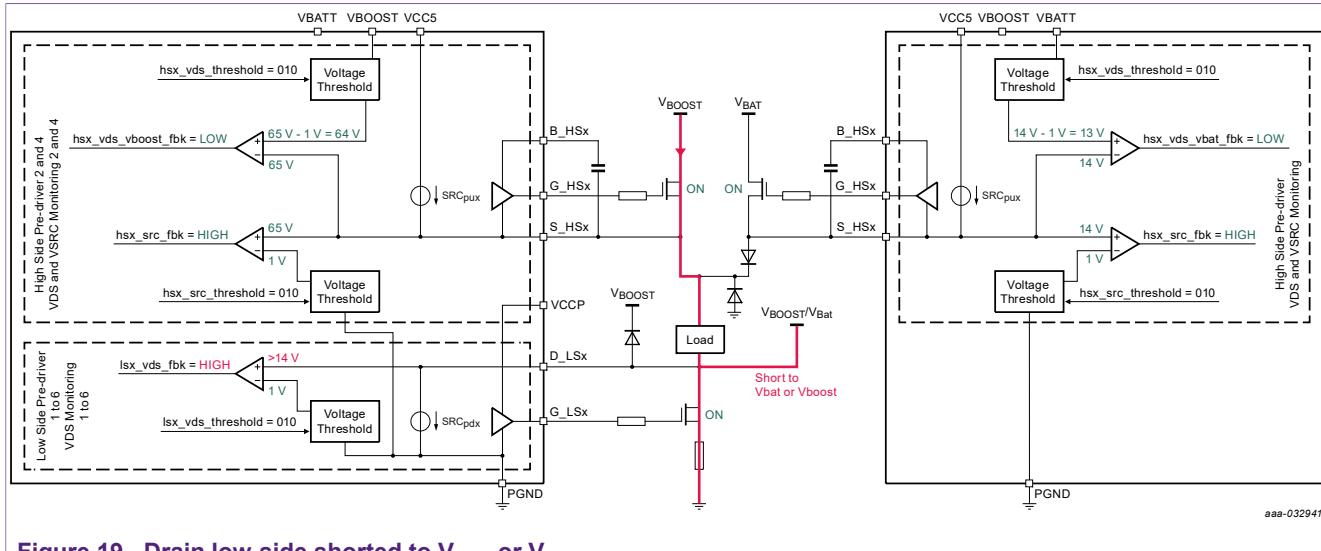


Figure 19. Drain low-side shorted to V_{BAT} or V_{BOOST}

This is the same behavior as in the peak and hold phase, when the drain low-side is shorted to V_{BAT} or V_{BOOST} (low probability), with a short to GND on V_{BOOST} or V_{BAT}. The automatic diagnostic fails, because the voltage on D_LSx is higher than the V_{DS} threshold.

Table 19. Drain low-side shorted to V_{BAT} or V_{BOOST} truth table

| Error case | LSx_vds_fbk | HSx_src_vbat_fbk | HSx_vds_Vbat_fbk | HSx_vds_Vboost_fbk | HSx_vsrc_Vboost_fbk |
|----------------------|-------------|------------------|------------------|--------------------|---------------------|
| Normal mode | 0 | 1 | 0 | 0 | 1 |
| D_LS boost/bat short | 1 | 1 | 0 | 0 | 1 |

5.2.2.6 Cases undetectable during boost mode

There are different cases undetectable in the boost phase:

- Drain low-side shorted to GND: not detectable, since the low-side is ON in this case (detectable in the idle phase)
- High-side V_{BAT} or V_{BOOST} drain source shorted: not detectable, since in this case, high-side is ON (detectable in the idle phase)
- High-side V_{BOOST} open: not detectable, since the high-side V_{BOOST} is OFF in this mode (detectable during the V_{BOOST} phase)
- A short on the high-side V_{BAT} source S_HSx (before diode): the high-side V_{BAT} is OFF in this mode, but detectable during the idle phase

6 Software

6.1 Interrupt state machine

The following state diagrams describe how the MCU knows which interrupt occurred and which fault has been detected during both automatic and software interrupts.

For injectors actuation and DCDC state diagram, see [AN4849](#).

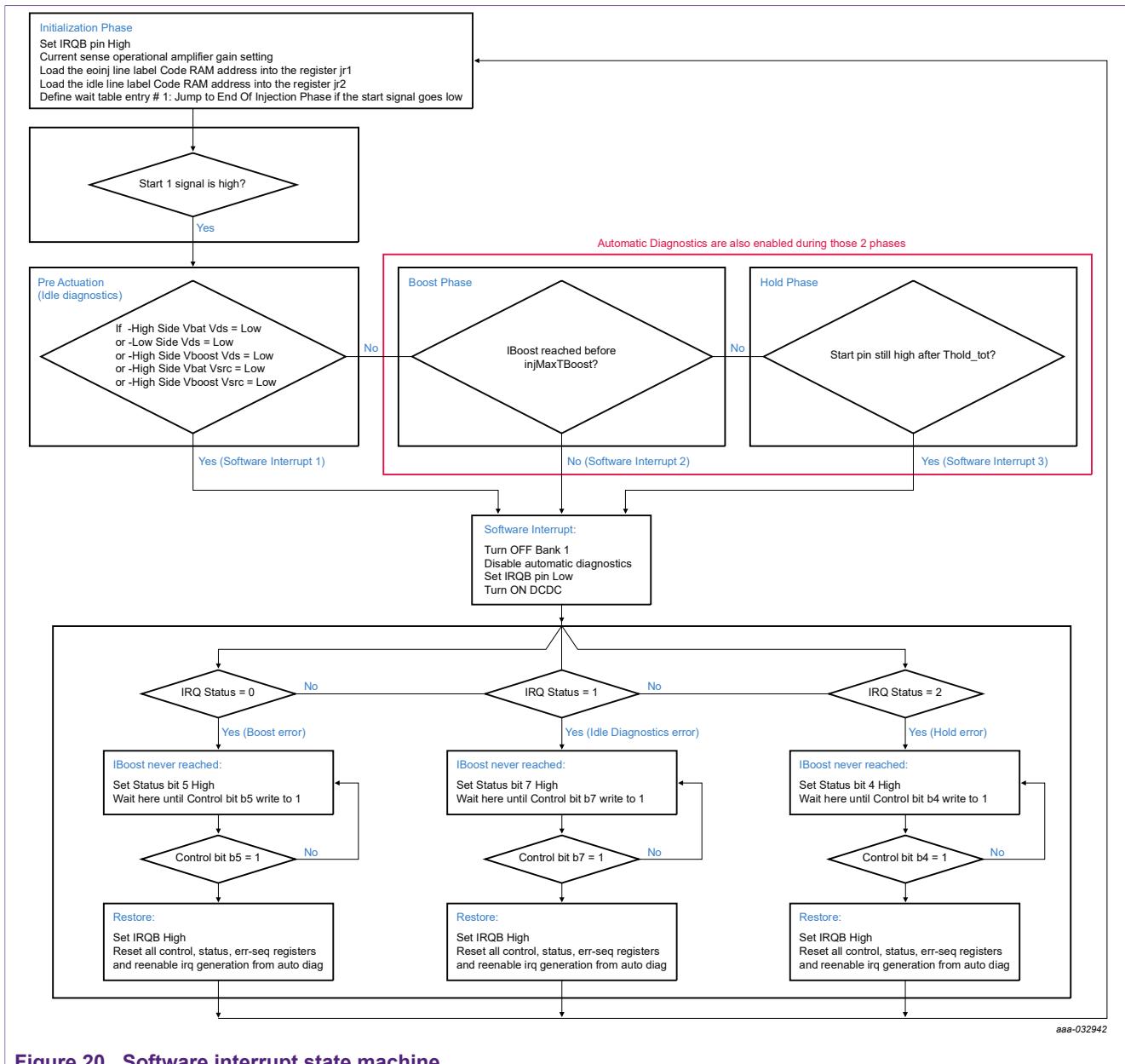


Figure 20. Software interrupt state machine

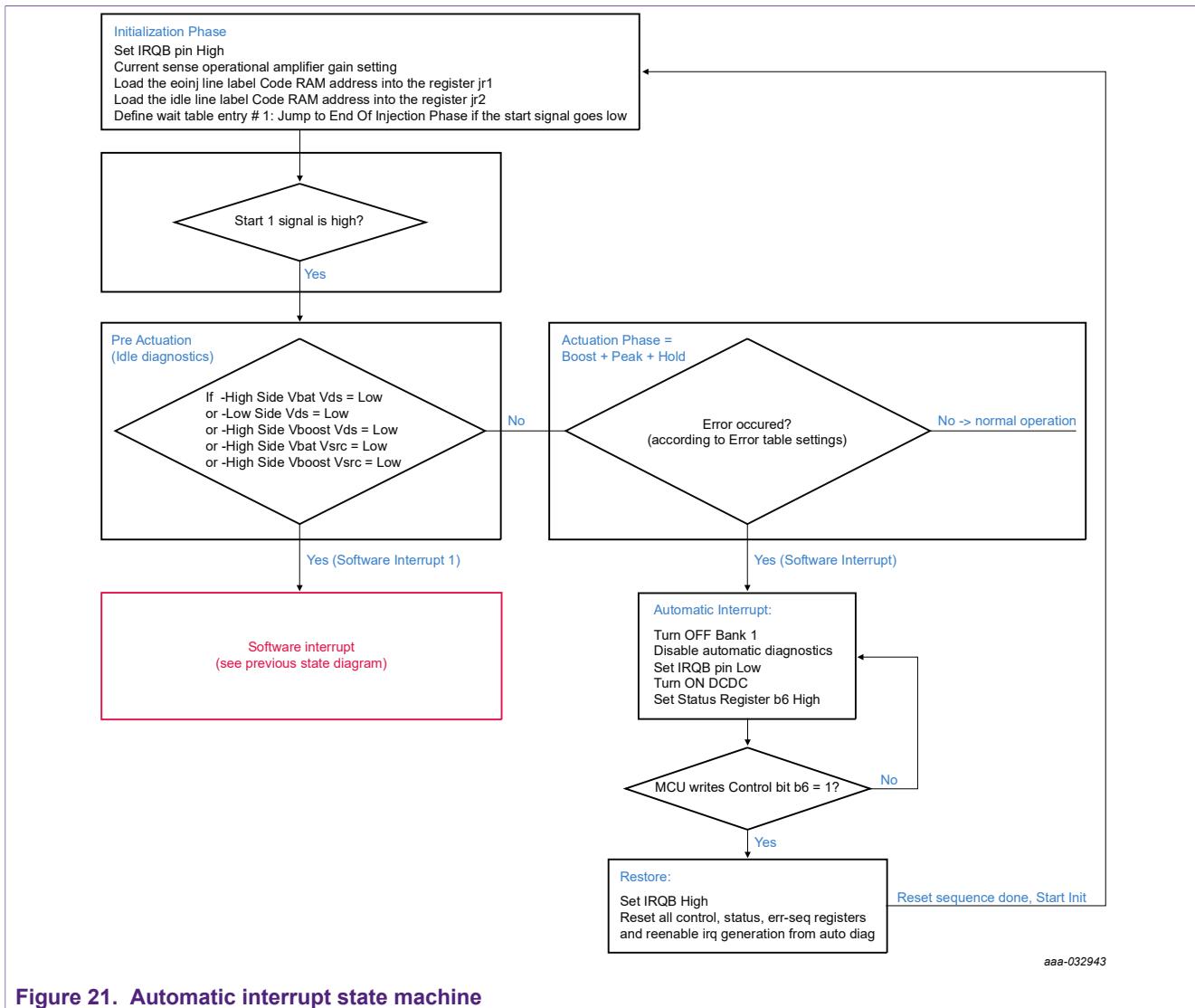


Figure 21. Automatic interrupt state machine

6.2 General registers setup

Unless specified, use the register settings described in [AN4849](#). Registers related to diagnostics and interrupts are described in the following sections.

6.2.1 Main configuration registers

Table 20. Driver_config register (0x1C5)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|-------------|-------------|---------|---------------|-------------------|------------------|---------------|---------------|-------------|-------------|---------|----------------|----------------|----------------|----------------|------------|
| Name | hs5_l36_ovr | vccp_ext_en | ls7_ovr | vboost_mon_en | vboost_disable_en | over_temp_irq_en | drv_en_irq_en | vboost_irq_en | vcc5_irq_en | vccp_irq_en | iret_en | irq_uc1_ch2_en | irq_uc0_ch2_en | irq_uc1_ch1_en | irq_uc0_ch1_en | irq_mcu_en |
| Value | X | X | X | X | X | X | X | X | 1 | X | X | X | X | X | X | 1 |

This register need not be set for the diagnostic on the external MOSFET, since it is handled in the microcode directly. If an error is detected, it forces IRQB low using the microcode. The return address (iret) is also determined in the microcode.

As an example, set vcc5_irq_en to '1', to force IRQB low in case of undervoltage on Vcc5. When the undervoltage is missing, the IRQB pin is kept low until the user writes a '1' in the uv_vcc5 bit (Driver_status register (0x1D2)).

6.2.2 IO configuration registers

This register (one for each microcore) selects the feedback by which each microcore is enabled. Setting the bit to '1' generates an interrupt towards UcXChY, in case an error is detected on the HSx or LSx feedback.

Table 21. Fbk_sens_uc0ch1 register (0x180)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|--------------|--------------|--------------|--------------|--------------|--------------|---------------|--------------|---------------|--------------|---------------|--------------|---------------|--------------|---------------|--------------|
| Name | ls6_vds_sens | ls5_vds_sens | ls4_vds_sens | ls3_vds_sens | ls2_vds_sens | ls1_vds_sens | hs5_vsrc_sens | hs5_vds_sens | hs4_vsrc_sens | hs4_vds_sens | hs3_vsrc_sens | hs3_vds_sens | hs2_vsrc_sens | hs2_vds_sens | hs1_vsrc_sens | hs1_vds_sens |
| Value | 0 | 1 | 0 | 0 | 1 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 1 | 1 | 1 |

In this particular application (see the schematics in [FRDMPT2001EVM](#)), microcore 0 channel 1 controls HS1 as high-side V_{BAT} and HS2 as high-side V_{BOOST} , LS1 and LS2. An interrupt is generated if an error occurs on LS2 V_{DS} , LS1 V_{DS} , HS2 V_{DS} , HS1 V_{DS} , HS2 V_{SRC} , and HS1 V_{SCR} (see [Table 21](#)).

6.2.2.1 PT2001 threshold settings

Each comparator threshold is set on four bits. The V_{DS} thresholds for high-side predrivers are defined by registers 0x1AE and 0x1AF. The V_{SRC} thresholds are defined by registers 0x1B0 and 0x1B1. The V_{DS} thresholds for low-side predrivers are defined by registers 0x1B2 and 0x1B3.

As described in fault description, these thresholds must be set according to the external MOSFET and maximum current level used in the application. As with FRDMPT2001EVM, the $R_{DS(on)}$ MOSFET is approximately equal to 24 mΩ (worst case condition). The maximum current used in this application is 16.09 A, and overcurrent detection (using V_{DS} monitoring) must be set at around 30 % higher than maximum current allowed (32 A).

Table 22. V_{DS} and V_{SRC} monitoring typical threshold selection

| hsx_vds/src_threshold(3:0) | Threshold voltage HS VDS / HS VSRC (V) |
|----------------------------|--|
| 0000 | 0.00 |
| 1001 | 0.10 |
| 1010 | 0.20 |
| 1011 | 0.30 |
| 1100 | 0.40 |
| 0001 | 0.50 |
| 0010 | 1.0 |
| 0011 | 1.5 |
| 0100 | 2.0 |
| 0101 | 2.5 |
| 0110 | 3.0 |
| 0111 | 3.5 |

6.2.2.1.1 High-side V_{DS} threshold calculation

V_{DS} threshold (HS) = Overcurrent $\times R_{DS(on)}$ = $32\text{ A} \times 0.025\text{ }\Omega = 0.8\text{ V} \rightarrow 1.0\text{ V}$ threshold selected. In this case, overcurrent = $1.0\text{ V}/0.025\text{ }\Omega = 40\text{ A}$.

Table 23. Vds_threshold_hs Part1 (1AEh)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|--------------|-------------|----|----|----|----|----|---|---|---|---|-------------|---|---|---|---|-------------|
| Name | Vds_thr_Hs4 | | | | | | | | | | Vds_thr_Hs2 | | | | | Vds_thr_Hs1 |
| R/W | R/W | | | | | | | | | | R/W | | | | | R/W |
| Lock | no | | | | | | | | | | no | | | | | no |
| Value | 0000 | | | | | | | | | | 0000 | | | | | 0000 |

Table 24. Vds_threshold_hs Part2 (1AFh)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|--------------|----------------|----|----|----|----|----|---|---|---|---|-------------|---|---|---|---|---|
| Name | reserved | | | | | | | | | | Vds_thr_Hs5 | | | | | |
| R/W | — | | | | | | | | | | R/W | | | | | |
| Lock | — | | | | | | | | | | no | | | | | |
| Value | 0000 0000 0000 | | | | | | | | | | 0000 | | | | | |

6.2.2.1.2 Low-side V_{DS} threshold calculation

Low-side the V_{DS} monitoring is done between D_LSx and GND, sense resistance must be included in the calculation.

V_{DS} threshold (LS) = Overcurrent $\times (R_{DS(on)} + R_{SENSE})$ = $32\text{ A} \times (0.025\text{ }\Omega + 0.015\text{ }\Omega) = 1.28\text{ V} \rightarrow 1.0\text{ V}$ threshold selected, in this case overcurrent = $1.0\text{ V} / 0.04\text{ }\Omega = 25\text{ A}$.

Table 25. Vds_threshold_ls Part1 (1B2h)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|--------------|-------------|----|----|----|----|----|---|---|---|---|-------------|---|---|---|---|-------------|
| Name | Vds_thr_Ls4 | | | | | | | | | | Vds_thr_Ls2 | | | | | Vds_thr_Ls1 |
| R/W | R/W | | | | | | | | | | R/W | | | | | R/W |
| Lock | no | | | | | | | | | | no | | | | | no |
| Value | 0000 | | | | | | | | | | 0000 | | | | | 0000 |

Table 26. Vds_threshold_ls Part2 (1B3h)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|--------------|-----------|----|----|----|----|----|---|---|---|---|-------------|---|---|---|---|-------------|
| Name | reserved | | | | | | | | | | Vds_thr_Ls6 | | | | | Vds_thr_Ls5 |
| R/W | — | | | | | | | | | | R/W | | | | | R/W |
| Lock | — | | | | | | | | | | no | | | | | no |
| Value | 0000 0000 | | | | | | | | | | 0000 | | | | | 0000 |

6.2.2.1.3 High-side SRC threshold

V_{SRC} is used mostly during idle phase to understand the type of fault present. It is better to keep the detection threshold far from the polarization condition. During actuation in this application, recirculation is done through a diode, keeping the voltage of the HS source below ground. In this case, any V_{SRC} voltage can be used, to prevent false diagnostics. In order to avoid detecting noise and to be far from the 3.8 V threshold, the PT2001 V_{SRC} threshold is set to 1.0 V.

Table 27. Vsrc_threshold_hs Part1 (1B0h)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|--------------|----|----|----|----|----|---|---|---|---|---|---|--------------|---|---|---|
| Name | Vsrc_thr_Hs4 | | | | | | | | | | | | Vsrc_thr_Hs2 | | | |
| R/W | R/W | | | | | | | | | | | | R/W | | | |
| Lock | no | | | | | | | | | | | | no | | | |
| Value | 0000 | | | | | | | | | | | | 0000 | | | |

Table 28. Vsrc_threshold_hs Part2 (1B1h)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------------|----|----|----|----|----|---|---|---|---|---|---|--------------|---|---|---|
| Name | reserved | | | | | | | | | | | | Vsrc_thr_Hs5 | | | |
| R/W | — | | | | | | | | | | | | R/W | | | |
| Lock | — | | | | | | | | | | | | no | | | |
| Value | 0000 0000 0000 | | | | | | | | | | | | 0000 | | | |

6.2.3 Channel 1 configuration registers

Unless specified, use the same settings specified in the [AN4849](#).

Table 29. Ctrl_reg_uc0 control registers for the microcore 0 (0x101, 0x121)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|-------------------------|----|----|----|----|----|---|---|---|---|---|---|------------------|---|---|---|
| Name | control_register_shared | | | | | | | | | | | | control_register | | | |
| Value | xxxxxxxx | | | | | | | | | | | | 00000000 | | | |

control_register: control bits 4, 5, 6, and 7 are used to control the turn ON of the bank after a fault occurs

- B4: if START pin is still high after t_{HOLD_TOT} is reached (see [Section 7 "Application source code"](#))
- B5: if I_{BOOST} is not reached before the specified time
- B6: if errors are detected during actuation (automatic diagnostics)
- B7: if errors are detected during pre-actuation phase (idle diagnostics)

Entry point for each microcode as specified, corresponds to the location in the CRAM where each microcontroller starts.

Table 30. Uc0_entry_point registers (0x10A, 0x12A)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|----|----|----|----|----|---|---|---|---|---|---|---------------------|---|---|---|
| Name | reserved | | | | | | | | | | | | entry_point_address | | | |
| Value | 000000 | | | | | | | | | | | | 100110000 | | | |

With the code provided, uc0 channel 1 starts line152 label *init0*, interrupt code should not be taken in account in the entry code.

Table 31. Uc1_entry_point registers (0x10B, 0x12B)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|----|----|----|----|----|---|---|---|---|---|---|---|---|---|---------------------|
| Name | reserved | | | | | | | | | | | | | | | entry_point_address |
| Value | 000000 | | | | | | | | | | | | | | | 000001000 |

With code provided, uc1 channel starts line 091 label *init1*.

It is required to specify the location in the CRAM, because the automatic interrupt is handled here.

Table 32. Diag_routine_addr registers (0x10C, 0x12C)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 | |
|-------|----------|----|----|----|----|----|---|---|---|---|-------------------------------|---|---|---|---|---|-------------------------------|
| Name | reserved | | | | | | | | | | diagnosis_routine_address_uc1 | | | | | | diagnosis_routine_address_uc0 |
| Value | 0000 | | | | | | | | | | xxxxxx | | | | | | 000000 |

- diagnosis_routine_address_uc0: automatic diagnostics are located at line 0 (label *irq_auto*)
- diagnosis_routine_address_uc1: not used in this example

The same settings on software interrupt are needed to specify the location in the CRAM where SW interrupts are handled.

Table 33. Sw_interrupt_routine_addr registers (0x10E, 0x12E)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|-------------------------------|------------------------------|-------------------------------|------------------------------|--|----|---|---|---|---|---|---|---|---|--|---|
| Name | sw_irq_falling_edge_start_uc1 | sw_irq_rising_edge_start_uc1 | sw_irq_falling_edge_start_uc0 | sw_irq_rising_edge_start_uc0 | software_interrupt_routine_address_uc1 | | | | | | | | | | software_interrupt_routine_address_uc0 | |
| Value | x | x | x | x | xxxxxx | | | | | | | | | | 000111 | |

- software_interrupt_routine_address_uc0: line 7 in the CRAM
- software_interrupt_routine_address_uc1: not used in this example
- sw_irq_rising_edge_start_uc0: not used in this example
- sw_irq_falling_edge_start_uc0: not used in this example

6.3 Diagnostics configuration registers

6.3.1 LS1 and LS2 output register

6.3.1.1 Filter time

These registers define the automatic diagnostics filtering. Values depend on noise in the application and MOSFET switching time to get stable for reliable feedback when diagnostics start.

Table 34. Lsx_diag_config1 registers (0x140, 0x143, 0x146, 0x149, 0x14C, 0x14F)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|----|-------------|---------------|----|----|---|---|---|---|---|---|---|----------------|---|---|
| Name | reserved | | filter_type | filter_length | | | | | | | | | | disable_window | | |
| Value | 00 | | 0 | 111011 | | | | | | | | | | 1011010 | | |

- filter_type: set to 0, in this case, means any different sample resets the filter counter
- filter_length: the filtering time is: $t_{FTN} = t_{CK} \times (5 + 1) = 1/6 \text{ MHz} \times 6 = 1 \mu\text{s}$

- **disable_window**: this 7-bit parameter configures a time period during which any check on the **LSx_Vds_feed** signal is disabled after any change on the **output_command** signal. $t_{DTL} = t_{CK} \times (14 + 4) = 1/6 \text{ MHz} \times 18 = 3.0 \mu\text{s}$

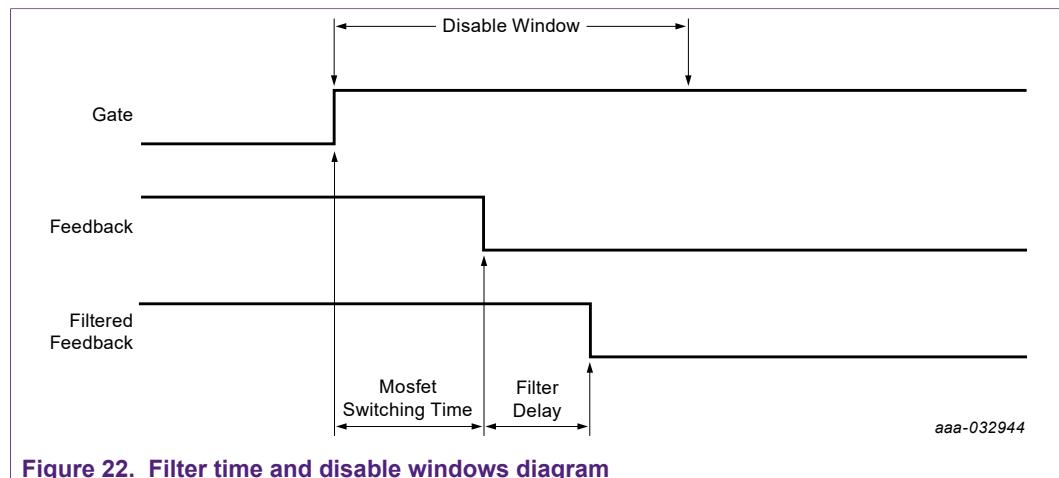


Figure 22. Filter time and disable windows diagram

6.3.1.2 Error table

Using [Section 5 "Diagnostic descriptions"](#), error tables can be easily generated.

Table 35. **Lsx_diag_config2** registers (0x141, 0x144, 0x147, 0x14A, 0x14D, 0x150)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|--------------|----|----|----|----|----|---|---|---|---|---|---|-------------|---|---|---|
| Name | reserved | | | | | | | | | | | | error_table | | | |
| Value | 000000000000 | | | | | | | | | | | | 1001 | | | |

- **error_table**: this 4-bit parameter defines the logical value of an error signal, issued from the output and the related V_{DS} feedback signal. This table defines the output of the coherency check between the driven output and the acquired feedback; a logic one value means there is no coherency in the check, and then an error signal towards the microcore should be generated.

Table 36. Error table for both low-sides

| | output_command = 0 (predriver switched OFF) | output_command = 1 (predriver switched ON) |
|---|---|--|
| lsx_vds_fbk = 0 (V_{DS} below threshold) | error_table (0) = 1 | error_table (2) = 0 (OK) |
| lsx_vds_fbk = 1 (V_{DS} above threshold) | error_table (1) = 0 (OK) | error_table (3) = 1 |

Normal mode in this application:

- Low-side is ON and the V_{DS} comparator should be low
- Low-side is OFF and the V_{DS} comparator should be high

6.3.2 HS1/HS2 output register

6.3.2.1 Filter time

Use the same filtering as the low-side, since the same MOSFET and slew rates are used for both.

Table 37. Hsx_diag_config_1 registers (0x153, 0x156, 0x159, 0x15C, 0x15F)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|-------------|---------------|----|----|----|---|---|---|---|---|---|----------------|---|---|---|
| Name | reserved | filter_type | filter_length | | | | | | | | | | disable_window | | | |
| Value | 00 | 0 | 111011 | | | | | | | | | | 1011010 | | | |

- filter_type: set to 0, in this case, means any different sample resets the filter counter
- filter_length: the filtering time is: $t_{FTN} = t_{CK} \times (5 + 1) = 1/6 \text{ MHz} \times 6 = 1 \mu\text{s}$
- disable_window: this 7-bit parameter configures a time period during which any check on the LSx_Vds_feed signal is disabled after any change on the output_command signal. $t_{DTL} = t_{CK} \times (14 + 4) = 1/6 \text{ MHz} \times 18 = 3.0 \mu\text{s}$

6.3.2.2 Error table

6.3.2.2.1 HS1 (VBAT) error table

Table 38. Hsx_diag_config_2 registers (0x154, 0x157, 0x115A, 0x15D, 0x160)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|----|----|----|----|----|---|---|---|---|-----------------|---|---|---|-----------------|---|
| Name | reserved | | | | | | | | | | error_table_src | | | | error_table_vds | |
| Value | 00000000 | | | | | | | | | | 0110 | | | | 1001 | |

Table 39. Error table for high-side V_{DS}

| | output_command = 0 (predriver switched OFF) | output_command = 1 (predriver switched ON) |
|---|---|--|
| hsx_vds_fbk = 0 (V _{DS} below threshold) | error_table_vds (0) = 1 | error_table_vds (2) = 0 |
| hsx_vds_fbk = 1 (V _{DS} above threshold) | error_table_vds (1) = 0 | error_table_vds (3) = 1 |

Normal mode in this application:

- High-side is ON and the V_{DS} comparator should be low
- High-side is OFF and the V_{DS} comparator should be high

Table 40. Error table for high-side V_{SRC}

| | output_command = 0 (predriver switched OFF) | output_command = 1 (predriver switched ON) |
|--|---|--|
| hsx_src_fbk = 0 (V _{SRC} below threshold) | error_table_src (0) = 0 | error_table_src (2) = 1 |
| hsx_src_fbk = 1 (V _{SRC} above threshold) | error_table_src (1) = 1 | error_table_src (3) = 0 |

Normal mode in this application:

- High-side is ON and the V_{SRC} comparator should be high
- High-side is OFF and the V_{SRC} comparator should be low

6.3.2.2.2 HS2 (VBOOST) error table

Table 41. Hsx_diag_config_2 registers (0x154, 0x157, 0x115A, 0x15D, 0x160)

| Bit | 15 | 14 | 13 | 12 | 11 | 10 | 9 | 8 | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 |
|-------|----------|----|----|----|----|----|---|---|---|---|-----------------|---|---|---|-----------------|---|
| Name | reserved | | | | | | | | | | error_table_src | | | | error_table_vds | |
| Value | 00000000 | | | | | | | | | | 0100 | | | | 1001 | |

| | output_command = 0 (predriver switched OFF) | output_command = 1 (predriver switched ON) |
|---|---|--|
| hsx_vds_fbk = 0 (V _{DS} below threshold) | error_table_vds (0) = 1 | error_table_vds (2) = 0 |
| hsx_vds_fbk = 1 (V _{DS} above threshold) | error_table_vds (1) = 0 | error_table_vds (3) = 1 |

| | output_command = 0 (predriver switched OFF) | output_command = 1 (predriver switched ON) |
|--|---|--|
| hsx_src_fbk = 0 (V _{SRC} below threshold) | error_table_src (0) = 0 | error_table_src (2) = 1 |
| hsx_src_fbk = 1 (V _{SRC} above threshold) | error_table_src (1) = 0 | error_table_src (3) = 0 |

V_{BOOST} high-side source detection is different in this application from V_{BAT} since S_{HSVbat} and S_{HS_VBoost} are shorted together through a diode. If V_{BAT} high-side is ON, voltage on the V_{BOOST} source high-side is equal to V_{PWR} - diode. Consequently, the PT2001 should not detect an error on high-side V_{BOOST} if command = 0 and source feedback = 1.

7 Application source code

The following microcode can be directly downloaded from the NXP web site (see [FRDMPT2001EVM](#)). Using the IDE and SPIGEN, the microcode can be downloaded to the PT2001.

7.1 Injection banks management source code

```
#include "AN_Diag_ch1.def";
*****
* Copyright (c) NXP 2016 *
* File Name: Pierre_test_4inj.dfi
* Current Revision: 1.0
* Purpose: PT2001 example - 1 Bank diagnostic
* Description: PT2001 Channel 1 main function provide peak and hold current
* profile for Uc0Ch1 and use idle and automatic diagnostics
* Uc1Ch1 provide peak and hold without diagnostics
*
* REV AUTHOR DATE DESCRIPTION OF CHANGE
* --- -----
* 1.0 b16868 2014/03/25 - initial coding
*
*****
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* occur. Should Buyer purchase or use NXP products for any such intended
* or unauthorized application, Buyer shall indemnify and hold NXP and
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* against all claims costs, damages, and expenses, and reasonable attorney fees
* arising out of, directly or indirectly, any claim of personal injury or
* death associated with such unintended or unauthorized use, even if such
* claim alleges that NXP was negligent regarding the design or
* manufacture of the part. NXP and the NXP logo are registered
* trademarks of NXP B.V.
*****
* ### Channel 1 - uCore0 controls the injectors 1 ###
* Constant definition
#define HSBoost_B1 hs2;
#define HSBAT_B1 hs1;
#define LS1_B1 ls1;
#define LS2_B1 ls2;
#####
* STATUS REGISTER #####
* This bit must be set to 1 if the Iboost current is never reached during the boost phase
#define BoostErrorBit b5;
* This bit must be set to 1 the sequencer is currently executing the Automatic interrupt routine
#define AutoIrqBit b6;
* This bit must be set to 1 the sequencer is currently executing the Idle Diag interrupt routine
#define IdleIrqBit b7;
* This bit must be set to 1 if start pin stays high longer than 10ms
#define HoldErrorBit b4;
```

```

* ##### FLAGS #####
* This flag is sent to the DCDC sequencer. It must be active for the whole period the boost voltage is used
* When the boost voltage is used, the DCDC must be deactivated
* flag = 0 => boost voltage is used, DCDC must be deactivated
* flag = 1 => boost voltage not used, DCDC can be active
#define BstFlag b0;

* ##### CONTROL REGISTER #####
* During the interrupt routine, the sequencer wait for this bit to be set to '1' before resuming execution of
application code
#define AutoDiagResetBit b6;
* During the interrupt routine, the sequencer wait for this bit to be set to '1' before resuming execution of
application code
#define IdleDiagResetBit b7;
* During the interrupt routine, the sequencer wait for this bit to be set to '1' before resuming execution of
application code
#define BoostResetBit b5;
* During the interrupt routine, the sequencer wait for this bit to be set to '1' before resuming execution of
application code
#define HoldResetBit b4;

* ##### ALU registers #####
#define IRQ_stat_Reg r0;

*****
* AUTOMATIC INTERRUPT
*****
irq_auto:    stos off off off;           * Disable drivers
             endiaga diagoff;        * Disable automatic diagnostic
             stirg low;             * Set the low IRQB pin
             stf high BstFlag;      * Set flag0 high DCDC active
             stsrh high AutoIrqBit; * Set status register bit 5 when automatic diagnosis
interrupt trig

auto_waitEnable:jcrr auto_waitEnable AutoDiagResetBit low; * the sequencer is stuck here until the bit of the
control register is set to '1' b6
             ldjrl restore;          * Load restore to jrl to do a jump far
             jmpf jrl;               * Jump to restore

*****
* SOFTWARE INTERRUPT
*****
irq1_sw:    stos off off off;           * Disable drivers
             endiaga diagoff;        * Disable automatic diagnostic
             stirg low;              * Set low the IRQB pin
             stf high BstFlag;       * Set flag0 high to release the DC-DC converter idle
mode

* Check which Sw interrupt occurred BoostErr 0 or Idle Diag Fail 1
cp irq IRQ_stat_Reg;           * copy the irq status registers to a temp ALU reg
                                * This register contains also the sw irq ID
                                * load MSB in ir reg: 0x0C00 in immediate register, to use as mask
ldirh 0Ch rst;
for irq status
    and IRQ_stat_Reg;          * extract the sw id from irq status register (bits 11-10)
    jarr Boost_waitEN all0;    * if the sw id is 0 => Iboost never reached => go to Boost_waitEN
                                * Else => error detected in idle diag=> go to next line => seq stuck until micro
write 1 in control register b8

    ldirh 08h rst;             * load MSB in ir reg: 0x0800 in immediate register, to
use as mask for irq status
    and IRQ_stat_Reg;          * extract the sw id from irq status register (bits 11-10)
                                * if the sw id is 0 => Means IRQ = b01 => Idle
                                * Else => Hold error => go to next line => idle diag
diagnostics fails

fail

Hold_waitEN:   stsrh high HoldErrorBit;
                jcrr Hold_waitEN HoldResetBit low;
                jmpf restore;          * Start pin stays higher longer than 10ms
                                * Wait here until control bit register is write to 1

sw_waitEnable:  stsrh high IdleIrqBit;
                which error occurred
                                jcrr sw_waitEnable IdleDiagResetBit low; * IDle diag fail we set status b8 high to let user know
                                jmpf restore;          * Wait here until control bit register is write to 1

Boost_waitEN:   stsrh high BoostErrorBit;
                register bit b5
                                jcrr Boost_waitEN BoostResetBit low; * Iboost never reached, let user know by setting status
                                * Wait here until control bit register is write to 1

restore:       stirg high;
                rstreg all;
                                * Set high IRQB pin
                                * Reset a) control registers
                                *          b) status register
                                *          c) err_seq register (status of automatic
diagnosis

```

```

diagnosis           *      d) re-enables irq generation from automatic
                   iret restart rst;           * Clear interrupt queue and restart from init phase

*****
*           INIT PHASE
*****
init0:   stirq high;           * Set high IRQB pin
         stgn gain8.68 sssc;   * Set gain amplifier for current feedback 1
         ldjrl eoinj0;         * Load end of injector in jrl to use jump far
         ldjr2 idle0;         * Load idle0 in jrl to use jump far
         cwef jrl _start row1; * If any start goes low go to eoi

*****
*           IDLE PHASE
*****
idle0:   joslr injel start1;  * Start injector 1 if start1 goes high
         joslr inje2 start2;  * Start injector 2 if start2 goes high
         jmpf jrl;           * Jump to end of injection

*****
*           SHORTCUT DEFINITION
*****
injel:   dfscs HSBAT_B1 LS1_B1 HSBoost_B1;  * Shortcut1 = HSVBAT, Shortcut2= LS2_B1, Shortcut3=
         HSBOOST
         dfcsct dac1;        * use current feedback1
         jmpm idle_diag0;   * Jump to idle_diag0

inje2:   dfscs HSBAT_B1 LS2_B1 HSBoost_B1;  * Shortcut1 = HSVBAT, Shortcut2= LS2_B1, Shortcut3=
         HSBOOST
         dfcsct dac1;        * use current feedback1
         jmpm idle_diag0;   * Jump to idle_diag0 (useless here)

*****
*           PRE-ACTUATION DIAG PHASE
*****
idle_diag0: bias all on;    * Enable all biasing structures, kept ON even during
actuation
         jocr idle_diag_fail0 _sc1v; * Error detected if Vds of shortcut1 (HS) is low
         jocr idle_diag_fail0 _sc2v; * Error detected if Vds of shortcut2 (LS) is low
         jocr idle_diag_fail0 _sc3v; * Error detected if Vds of shortcut3 (Boost) is low
         jocr idle_diag_fail0 _sc1s; * Error detected if Vsrc of shortcut1 (HS) is low
         jocr idle_diag_fail0 _sc3s; * Error detected if Vsrc of shortcut3 (Boost) is low
         jmpm boost0;           * Jump to actuation phase if no failure detected in idle
phase

idle_diag_fail0: reqi 1;    * Go to software subroutine if fault detected in idle
phase HSBat error

*****
*           BOOST PHASE
*****
boost0:  ldcd rst _ofs keep keep injMaxTBoost c3; * Start Boost Counter in case Iboost never reached
         load Iboost dac_sssc _ofs;  * Load Boost current threshold
         cwer peak0 curl row2;     * Define Wait Table Iboost is reached and jump to peak phase
         cwer boost_err0 tc3 row5; * Define Wait Table if actuation longer than injMaxGuard go
to
eoinj (added from AN4849)

         stf low BstFlag;        * Turn OFF the boost during this phase
         stos on on on;         * Vbat high-side On, Vboost HS On et LS1/2 ON, need to turn
ON
HS1 also to avoid diag failure
endiags on on on on;           * Enable auto diag

         wait row125;           * Wait start goes low or Iboost reached or InjMaxTBoost reached
boost_err0: reqi 0;           * Go to software subroutine if fault detected in Boost
phase, did not reach Iboost on time (added from AN4849)

*****
*           PEAK PHASE
*****
peak0:   ldcd rst _ofs keep keep Tpeak_tot c1; * Start Tpeak tot counter
         stf high BstFlag;      * Turn Boost back on
         load Ipeak dac_sssc _ofs; * Load the peak current threshold in the current DAC
         cwer bypass0 tc1 row2; * Define Wait: Jump to bypass phase when tc1 reaches end of
count
         cwer peak_on0 tc2 row3; * Define Wait: Jump to peak_on when tc2 reaches end of count
         cwer peak_off0 occur row4; * Define Wait: Jump to peak_off when current is over
threshold

peak_on0:  stos on on off;   * Vbat On LS On, if needed Boost HS can stay ON during this
phase
         wait row124;

peak_off0: ldcd rst ofs keep keep Tpeak_off c2; * Load in the counter 2 the length of the peak_off phase

```

```

stos off on off;                                * turn OFF HSvbat keep LS ON
wait row123;

*****
*          BYPASS PHASE
*****
bypass0: ldcd rst ofs keep keep Tbypass c3;    * Load in the counter 3 the length of the off_phase phase
stos off off off;                                * turn OFF all HS LS1/2
cwer hold0 tc3 row4;                                * Define Wait: Jump to hold when tc3 reaches end of count
wait row14;

*****
*          HOLD PHASE
*****
hold0: ldcd rst _ofs keep keep Thold_tot c1;    * load thold tot inside c1
load Ihold dac_sssc_ofs;                                * load hold current inside DAC
cwer hold_error0 tcl row2;                                * Define Wait: Jump to hold error if start still high after

thold tot
cwer hold_on0 tc2 row3;                                * Define Wait: Jump to hold on after thold off
cwer hold_off0 curl1 row4;                                * Define Wait: Jump to hold off when current Ihold reached
hold_on0: stos on on off;                                * HSvbat ON, LS ON
wait row124;

hold_off0: ldcd rst _ofs keep keep Thold_off c2;    * load thold off inside c2
stos off on off;                                * LS ON
wait row123;

hold_error0: req1 2;                                * If Start high is longer than Thold_tot go to sw interrupt

*****
*          END OF INJECTION PHASE
*****
eoinj0: stos off off off;                                * disable auto diag
endiags off off off;                                * turn ON DCDC
stf high BstFlag;                                * jump to idle

#####
#####
#####

* ### Channel 1 - uCore1 controls injectors 3 and 4 without diagnostics ###
* ### Variables declaration ###

* Note: The data that defines the profiles are shared between the two microcores.

* ### Initialization phase ###
init1: stgn gain8.68 sssc;                                * Set the gain of the opamp of the current measure block 2
ldjrl eoinj1;                                * Load the eoinj line label Code RAM address into the register jr1
ldjrl2 idle1;                                * Load the idle line label Code RAM address into the register jr2
cweff jr1 _start row1;                                * If the start signal goes low, go to eoinj phase

* ### Idle phase- the uPC loops here until start signal is present ###
idle1: josrl inj3_start start3;                                * Perform an actuation on inj3 if start 3 (only) is active
josrl inj4_start start4;                                * Perform an actuation on inj4 if start 4 (only) is active
jmpf jr1;                                * If more than 1 start active at the same time(or none), no actuation

* ### Shortcuts definition per the injector to be actuated ###
inj3_start: dfscs hs3 hs4 ls3;                                * Set the 3 shorcuts : VBAT, VBOOST, LS
jmpf boost1;                                * Jump to launch phase

inj4_start: dfscs hs3 hs4 ls4;                                * Set the 3 shorcuts : VBAT, VBOOST, LS
jmpf boost1;                                * Jump to launch phase

* ### Launch phase enable boost ###
boost1: load Iboost dac_sssc_ofs;                                * Load the boost phase current threshold in the current DAC
cwer peak1 occur row2;                                * Jump to peak phase when current is over threshold
stf low b0;                                * set flag0 low to force the DC-DC converter in idle mode
stos off on on;                                * Turn VBAT off, BOOST on, LS on
wait row12;                                * Wait for one of the previously defined conditions

* ### Peak phase continue on Vbat ###
peak1: ldcd rst _ofs keep keep Tpeak_tot c1;* Load the length of the total peak phase in counter 1
load Ipeak dac_sssc_ofs;                                * Load the peak current threshold in the current DAC
cwer bypass1 tcl row2;                                * Jump to bypass phase when tcl reaches end of count
cwer peak_on1 tc2 row3;                                * Jump to peak_on when tc2 reaches end of count
cwer peak_off1 occur row4;                                * Jump to peak_off when current is over threshold
stf high b0;                                * set flag0 high to release the DC-DC converter idle mode

peak_on1: stos on off on;                                * Turn VBAT on, BOOST off, LS on
wait row124;                                * Wait for one of the previously defined conditions

```

```

peak_off1: ldcd rst ofs keep keep Tpeak off c2;* Load in the counter 2 the length of the peak_off phase
    stos off off on;                      * Turn VBAT off, BOOST off, LS on
    wait row123;                         * Wait for one of the previously defined conditions

* ### Bypass phase ###
bypass1:  ldcd rst ofs keep keep Tbypass c3;* Load in the counter 3 the length of the off_phase phase
    stos off off off;                    * Turn VBAT off, BOOST off, LS off
    cwer hold1 tc3 row4;                * Jump to hold when tc3 reaches end of count
    wait row14;                         * Wait for one of the previously defined conditions

* ### Hold phase on Vbat ###
hold1:   ldcd rst _ofs keep keep Thold_tot c1;* Load the length of the total hold phase in counter 2
    load Ihold dac_sssc _ofs;          * Load the hold current threshold in the DAC
    cwer eoinj1 tcl row2;              * Jump to eoinj phase when tcl reaches end of count
    cwer hold_on1 tc2 row3;            * Jump to hold_on when tc2 reaches end of count
    cwer hold_off1 occur row4;        * Jump to hold_off when current is over threshold

hold_on1: stos on off on;                  * Turn VBAT on, BOOST off, LS on
    wait row124;                         * Wait for one of the previously defined conditions

hold_off1: ldcd rst _ofs keep keep Thold_off c2;* Load the length of the hold_off phase in counter 1
    stos off off on;                   * Turn VBAT off, BOOST off, LS on
    wait row123;                         * Wait for one of the previously defined conditions

* ### End of injection phase ###
eoinj1:  stos off off off;                * Turn VBAT off, BOOST off, LS off
    stf high b0;                      * set flag0 to high to release the DC-DC converter idle mode
    jmpf jr2;                          * Jump back to idle phase

* ### End of Channel 1 - uCore1 code ###

```

7.2 DC-DC and fuel pump source code

```

#include "AN_Diag_ch2.def";
*****
*                                         Copyright (c) NXP 2014
* File Name: Pierre_test_4inj.dfi
* Current Revision: 1.0
* Purpose: PT2001 example - 4 injectors control with Peak & Hold
* Description: PT2001 Channel 1 main function provide peak and hold current
* profile for Uc0Ch1 and Uc1Ch1
* File created by: NXP Analog, Tempe
*
* UPDATE HISTORY
* REV AUTHOR DATE      DESCRIPTION OF CHANGE
* --- ----- -----
* 1.0 b16868 2014/03/25 - initial coding
*
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*****
* ### Channel 2 - uCore0 controls the DCDC ###

##### INIT #####
init0:  stgn gain5.8 ossc;
        load Iboost_L dac_osc1_ofs;  *load DAC 4 L with low Vboost current
        load Iboost_H dac4h4n_ofs;  *load DAC 4H with high Vboost current
        stdm null;                 *Set DAC access mode to Vboost
        cwer idle0_f0 row1;
        cwer dcdcon_vb row2;        *if vboost lower than vboost low then turn on boost
        cwer dcdcoff_vb row3;       *if vboost higher than vboost high then turn off boost

```

```

dcdcon:    load Vboost_H dac4h4n _ofs;      *set Vboost high
            stdcctl async;          *set dc当地 to async
            wait row13;

dcdcoff:   load Vboost_L dac4h4n _ofs;      *set Vboost low
            stdcctl sync;          *set dc当地 to sync
            wait row12;

idle0:     stdcctl sync;
            jocr idle0 _f0;
            jmpf dcdcoff;

* ### End of Channel 2 - uCore0 code
#####
* ### Channel 2 - uCore1 drives fuel pump ###

* ### Variables declaration ###
* Note: The data are stored into the dataRAM of the channel 1.
#define Ipeak 5;          ** The peak current value is stored in the Data RAM address 5
#define Ihold 6;          ** The hold current value is stored in the Data RAM address 6
#define Thold_off 7;      ** The hold off time is stored in the Data RAM address 7
#define Thold_tot 8;      ** The hold phase duration is stored in the Data RAM address 8

* Note: The Tpeak_tot variable defines the current profile time out. The active STARTx pin is expected to toggle
in is low state before this time out.

* ### Initialization phase ###
init1:  stgn gain19.4 ossc;                  * Set the gain of the opamp of the current measure block 1
        ldjrl eoinj1;                      * Load the eoinj line label Code RAM address into the register jrl
        ldjrl2 idle1;                     * Load the idle line label Code RAM address into the register jrl2
        cwef jrl _start row1;             * If the start signal goes low, go to eoinj phase

* ### Idle phase- the uPC loops here until start signal is present ###
idle1:  joslr act5_start start5;            * Perform an actuation on act5 if start 5 (only) is active
        joslr act6_start start6;            * Perform an actuation on act6 if start 6 (only) is active
        jmpf jrl;                         * If more than 1 start active at the same time(or none), no
actuation

* ### Shortcuts definition per the injector to be actuated ###
act5_start: dfscs hs5 ls5 undef;          * Set the 2 shortcuts: VBAT, LS
        jmpf peak1;                      * Jump to launch phase
act6_start: dfscs hs5 ls6 undef;          * Set the 2 shortcuts: VBAT, LS
        jmpf peak1;                      * Jump to launch phase

* ### Launch peak phase on bat ###
peak1:  load Ipeak dac_oscsc_ofs;
        cwer hold1 cur3 row2;
        stos on on keep;
        wait row12;                      * Load the boost phase current threshold in the current DAC
                                         * Jump to peak phase when current is over threshold
                                         * Turn VBAT off, BOOST on, LS on
                                         * Wait for one of the previously defined conditions

* ### Hold phase on Vbat ###
hold1:  ldcd rst _ofs keep keep Thold_tot c1;
        load Thold dac_oscsc_ofs;
        cwer eoact1 tcl row2;
        cwer hold_on1 tc2 row3;
        cwer hold_off1 cur3 row4;
hold_on1: stos on on keep;
        wait row124;                     * Load the length of the total hold phase in counter 2
                                         * Load the hold current threshold in the DAC
                                         * Jump to eoinj phase when tcl reaches end of count
                                         * Jump to hold_on when tc2 reaches end of count
                                         * Jump to hold_off when current is over threshold
                                         * Turn VBAT on, LS on
                                         * Wait for one of the previously defined conditions
hold_off1: ldcd rst _ofs off on Thold_off c2;
        off, LS on
        wait row123;                     * Load the length of the hold_off phase in counter 1 and turn VBAT
                                         * Wait for one of the previously defined conditions

* ### End of injection phase ###
eoact1: stos off off keep;
        jmpf jr2;                         * Turn VBAT off, LS off
                                         * Jump back to idle phase

* ### End of Channel 2 - uCore1 code ###

```

8 References

- [1] **PT2001** — product summary page <http://www.nxp.com/PT2001>
- [2] **FRDMPT2001EVM** — tool summary page <http://www.nxp.com/FRDMPT2001EVM>
- [3] **AN4849** — Four injector and fuel pump drive application note https://www.nxp.com/files-static/analog/doc/app_note/AN4849.pdf
- [4] **AN12336SW** — SPI config file http://www.nxp.com/files/analog/doc/app_note/AN12336SW.zip

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Tables

| | | |
|----------|---|----|
| Tab. 1. | Example of injection current profile key parameters | 4 |
| Tab. 2. | Status_reg_uc0 registers (0x105) configuration | 5 |
| Tab. 3. | Ctrl_reg_uc0 registers (0x101) configuration | 5 |
| Tab. 4. | Normal mode truth table | 8 |
| Tab. 5. | S_HSx or D_LSx shorted to GND truth table | 9 |
| Tab. 6. | Drain source low-side shorted truth table | 10 |
| Tab. 7. | Drain source high-side shorted truth table | 11 |
| Tab. 8. | Openload truth table | 12 |
| Tab. 9. | Actuation in Normal mode truth table | 13 |
| Tab. 10. | High-side source shorted to GND truth table | 14 |
| Tab. 11. | High-side VBOOST drain source shorted truth table | 15 |
| Tab. 12. | High-side VBAT open truth table | 16 |
| Tab. 13. | Low-side open truth table | 16 |
| Tab. 14. | D_LS battery short truth table | 17 |
| Tab. 15. | Boost phase normal mode truth table | 18 |
| Tab. 16. | High-side boost source shorted to GND truth table | 19 |
| Tab. 17. | High-side boost open truth table | 19 |
| Tab. 18. | Low-side open truth table | 20 |
| Tab. 19. | Drain low-side shorted to VBAT or VBOOST truth table | 21 |
| Tab. 20. | Driver_config register (0x1C5) | 23 |
| Tab. 21. | Fbk_sens_uc0ch1 register (0x180) | 24 |
| Tab. 22. | VDS and VSRC monitoring typical threshold selection | 24 |
| Tab. 23. | Vds_threshold_hs Part1 (1AEh) | 25 |
| Tab. 24. | Vds_threshold_hs Part2 (1AFh) | 25 |
| Tab. 25. | Vds_threshold_ls Part1 (1B2h) | 25 |
| Tab. 26. | Vds_threshold_ls Part2 (1B3h) | 25 |
| Tab. 27. | Vsrc_threshold_hs Part1 (1B0h) | 26 |
| Tab. 28. | Vsrc_threshold_hs Part2 (1B1h) | 26 |
| Tab. 29. | Ctrl_reg_uc0 control registers for the microcore 0 (0x101, 0x121) | 26 |
| Tab. 30. | Uc0_entry_point registers (0x10A, 0x12A) | 26 |
| Tab. 31. | Uc1_entry_point registers (0x10B, 0x12B) | 27 |
| Tab. 32. | Diag_routine_addr registers (0x10C, 0x12C) | 27 |
| Tab. 33. | Sw_interrupt_routine_addr registers (0x10E, 0x12E) | 27 |
| Tab. 34. | Lsx_diag_config1 registers (0x140, 0x143, 0x146, 0x149, 0x14C, 0x14F) | 27 |
| Tab. 35. | Lsx_diag_config2 registers (0x141, 0x144, 0x147, 0x14A, 0x14D, 0x150) | 28 |
| Tab. 36. | Error table for both low-sides | 28 |
| Tab. 37. | Hsx_diag_config_1 registers (0x153, 0x156, 0x159, 0x15C, 0x15F) | 29 |
| Tab. 38. | Hsx_diag_config_2 registers (0x154, 0x157, 0x115A, 0x15D, 0x160) | 29 |
| Tab. 39. | Error table for high-side VDS | 29 |
| Tab. 40. | Error table for high-side VSRC | 29 |
| Tab. 41. | Hsx_diag_config_2 registers (0x154, 0x157, 0x115A, 0x15D, 0x160) | 29 |

Figures

| | | |
|----------|--|----|
| Fig. 1. | Typical four injector two bank application schematic | 3 |
| Fig. 2. | Typical peak and hold current profile with diagnostics | 6 |
| Fig. 3. | Biassing voltage vs. VBATT | 7 |
| Fig. 4. | Idle normal mode | 8 |
| Fig. 5. | High-side source or low-side drain shorted | 9 |
| Fig. 6. | Low-side drain source shorted | 10 |
| Fig. 7. | High-side drain source shorted | 11 |
| Fig. 8. | Openload | 12 |
| Fig. 9. | Normal mode peak and hold | 13 |
| Fig. 10. | High-side source shorted to GND | 14 |
| Fig. 11. | High-side VBOOST shorted | 15 |
| Fig. 12. | High-side open | 15 |
| Fig. 13. | Low-side open | 16 |
| Fig. 14. | Drain low-side shorted | 17 |
| Fig. 15. | Boost phase normal mode | 18 |
| Fig. 16. | High-side source shorted to GND | 18 |
| Fig. 17. | High-side VBOOST open | 19 |
| Fig. 18. | Low-side open | 20 |
| Fig. 19. | Drain low-side shorted to VBAT or VBOOST | 20 |
| Fig. 20. | Software interrupt state machine | 22 |
| Fig. 21. | Automatic interrupt state machine | 23 |
| Fig. 22. | Filter time and disable windows diagram | 28 |

Contents

| | | |
|----------|--|-----------|
| 1 | Introduction | 3 |
| 2 | Overview | 3 |
| 3 | Application schematic | 3 |
| 4 | Application instructions | 4 |
| 5 | Diagnostic descriptions | 5 |
| 5.1 | Idle diagnostics (pre-actuation) | 6 |
| 5.1.1 | Normal behavior | 8 |
| 5.1.2 | High-side source or low-side drain shorted to GND | 9 |
| 5.1.3 | Drain source low-side shorted to GND | 10 |
| 5.1.4 | Drain source high-side shorted to VBAT | 11 |
| 5.1.5 | Openload | 12 |
| 5.1.6 | Faults not detected in idle phase | 12 |
| 5.2 | Actuation phase | 13 |
| 5.2.1 | Actuation diagnostics peak and hold phase (HS Boost OFF, HS Bat ON, LS ON) | 13 |
| 5.2.1.1 | Normal mode | 13 |
| 5.2.1.2 | High-side (Bat or Boost) source shorted to GND | 14 |
| 5.2.1.3 | High-side VBOOST short drain source | 15 |
| 5.2.1.4 | High-side VBAT open | 15 |
| 5.2.1.5 | Low-side open | 16 |
| 5.2.1.6 | Drain low-side shorted to VBAT or VBOOST | 17 |
| 5.2.1.7 | Cases undetectable during peak and hold phase | 17 |
| 5.2.2 | Actuation diagnostics boost phase (HS Boost ON, HS Bat ON, LS ON) | 17 |
| 5.2.2.1 | Normal mode | 18 |
| 5.2.2.2 | High-side boost source shorted to GND | 18 |
| 5.2.2.3 | High-side VBOOST open | 19 |
| 5.2.2.4 | Low-side open | 20 |
| 5.2.2.5 | Drain low-side shorted to VBAT or VBOOST | 20 |
| 5.2.2.6 | Cases undetectable during boost mode | 21 |
| 6 | Software | 21 |
| 6.1 | Interrupt state machine | 21 |
| 6.2 | General registers setup | 23 |
| 6.2.1 | Main configuration registers | 23 |
| 6.2.2 | IO configuration registers | 24 |
| 6.2.2.1 | PT2001 threshold settings | 24 |
| 6.2.3 | Channel 1 configuration registers | 26 |
| 6.3 | Diagnostics configuration registers | 27 |
| 6.3.1 | LS1 and LS2 output register | 27 |
| 6.3.1.1 | Filter time | 27 |
| 6.3.1.2 | Error table | 28 |
| 6.3.2 | HS1/HS2 output register | 28 |
| 6.3.2.1 | Filter time | 28 |
| 6.3.2.2 | Error table | 29 |
| 7 | Application source code | 30 |
| 7.1 | Injection banks management source code | 30 |
| 7.2 | DC-DC and fuel pump source code | 34 |
| 8 | References | 35 |
| 9 | Legal information | 36 |

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